

Temporal diagnostics of femtosecond e-bunches via X-ray intensity interferometry

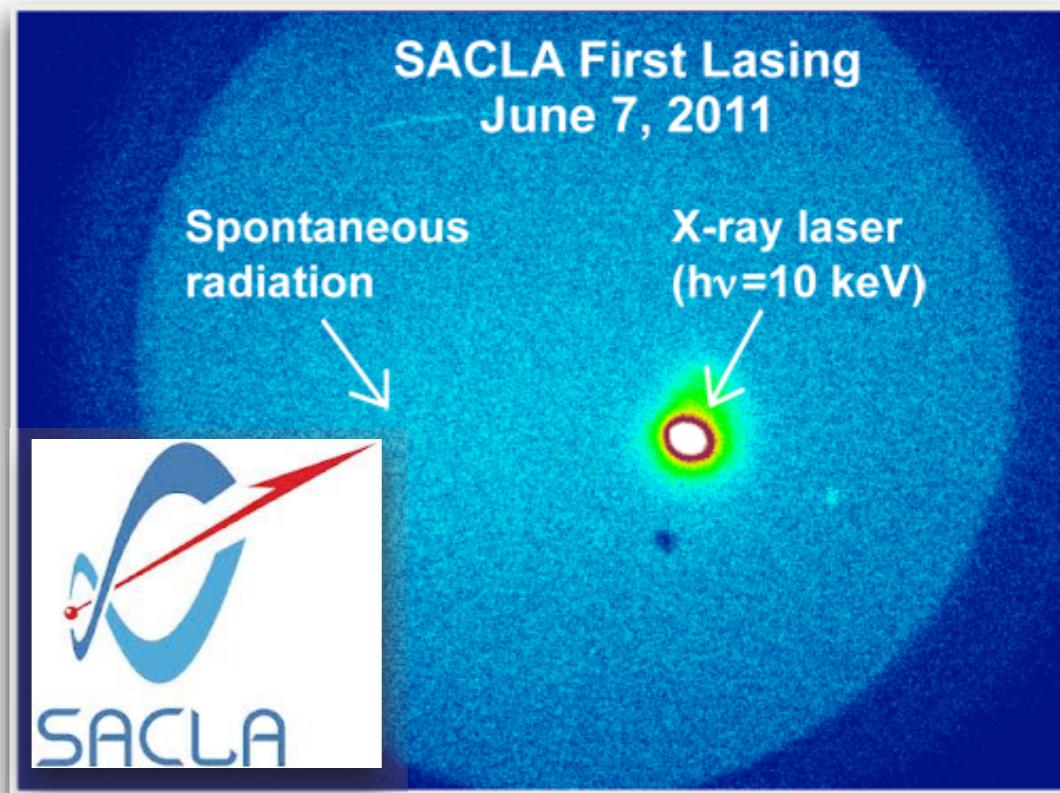
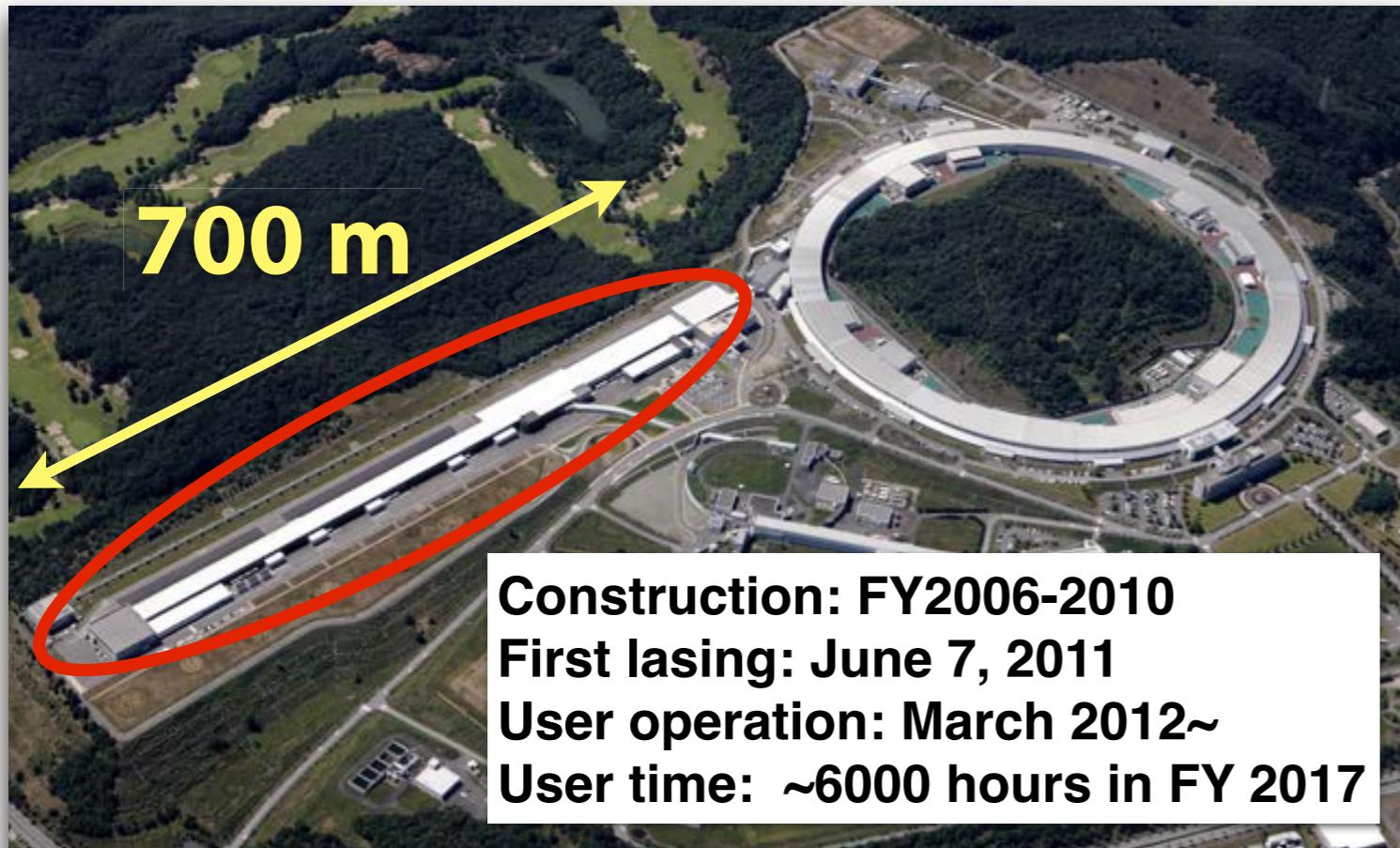
*“Simple & cost effective way to measure
attosecond/femtosecond e-bunch duration”*

Ichiro Inoue, Toru Hara, Yuichi Inubushi,
Hitoshi Tanaka, and Makina Yabashi

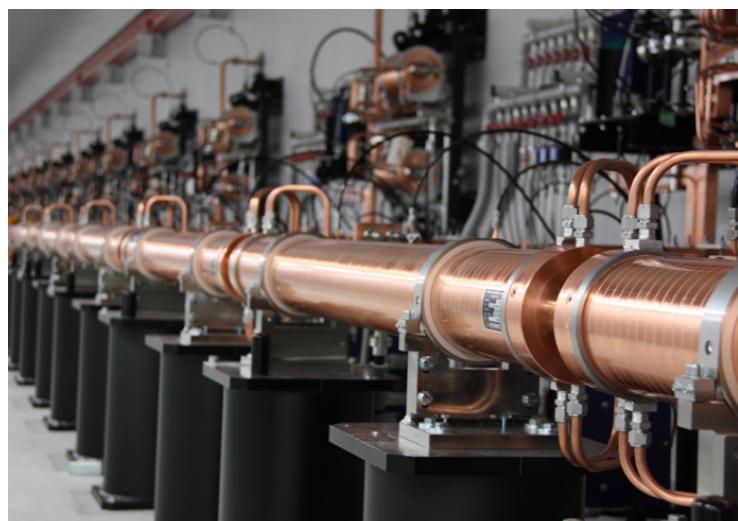
RIKEN SPring-8 Center / SACLÀ



SPring-8 **A**ngstrom **C**ompact free-electron **L**Aser “SACLA”



High gradient C-band accelerator
(acceleration gradient: 35 MV/m)



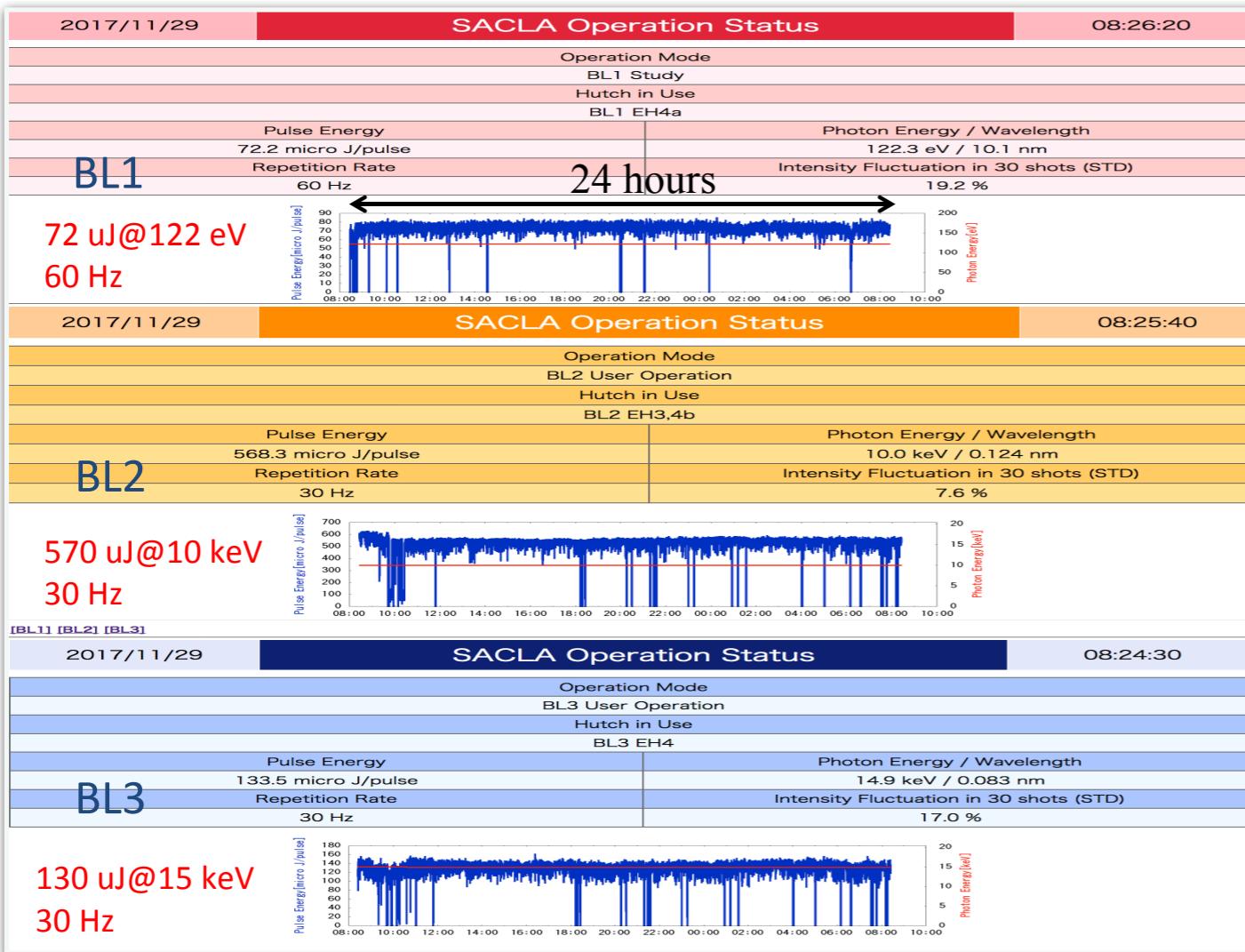
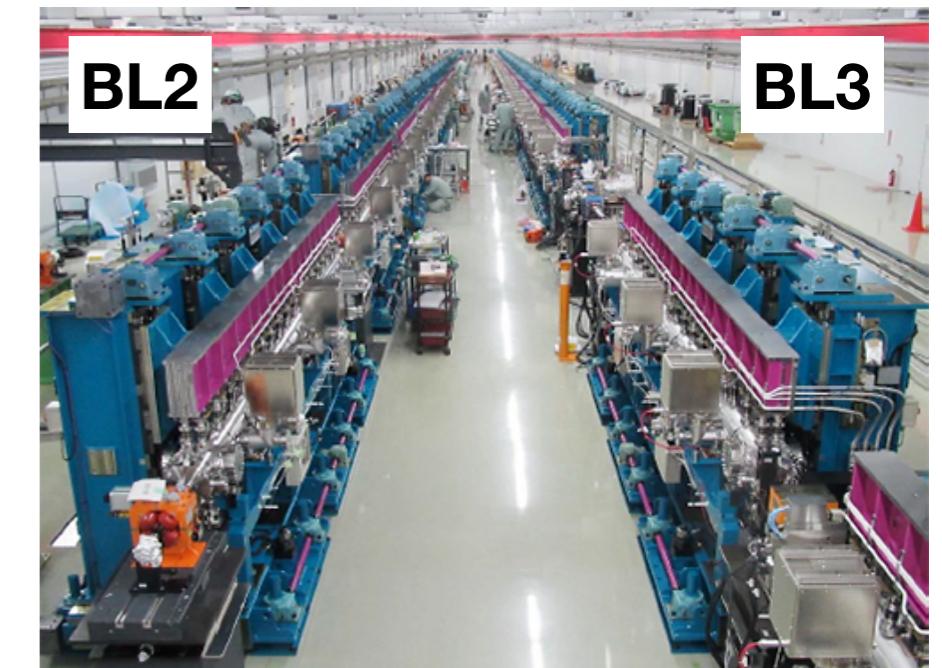
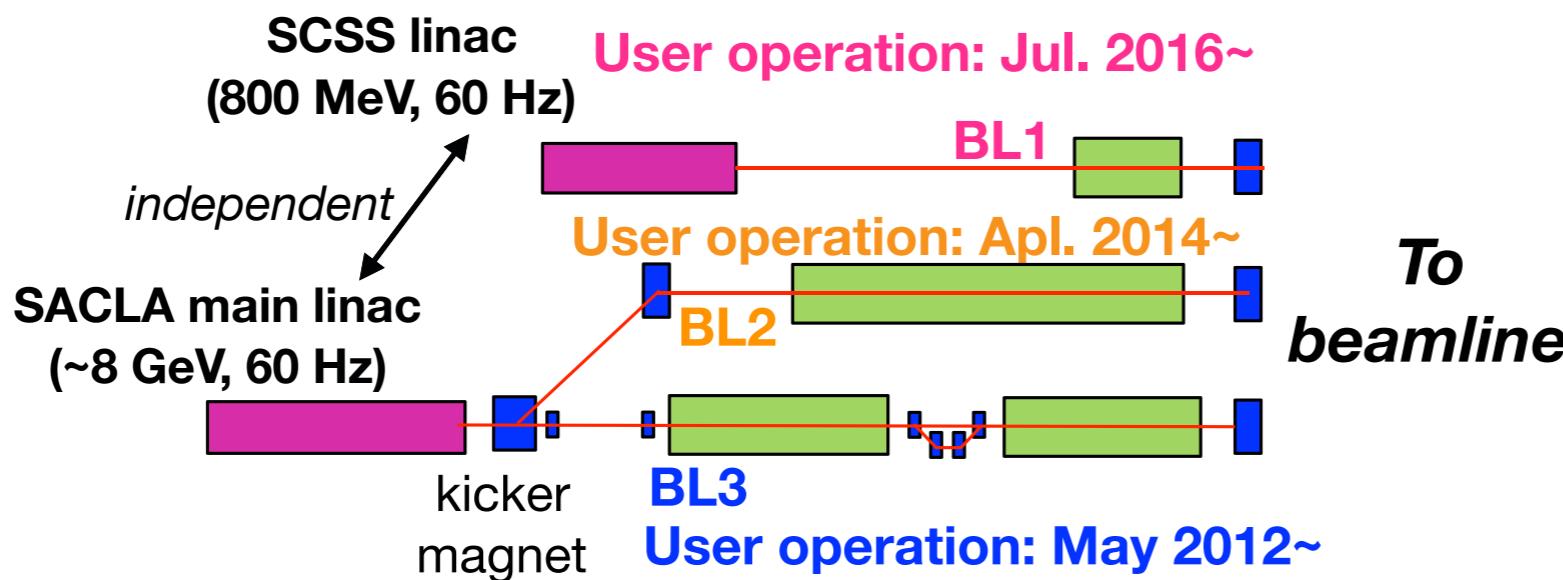
In-vacuum short period undulator ($\lambda_u=18$ mm)



XFEL amplification can be achieved at a relatively short distance (~700 m)

Current layout of SACL

Accelerator & undulator



of undulators

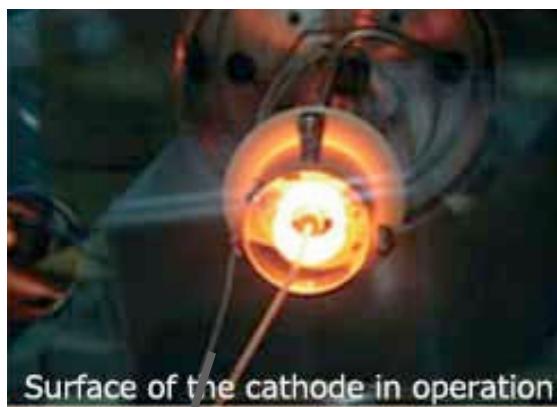
BL1: und. $\times 3$

BL2: und. $\times 18$

BL3: und. $\times 8$ + und. $\times 13$

Configuration of SACLAC accelerator

Low-emittance
thermionic gun

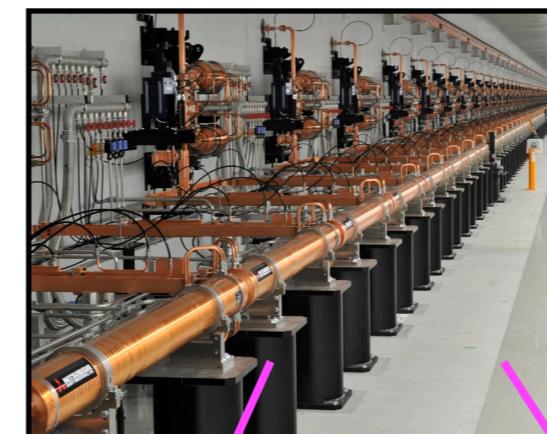


Surface of the cathode in operation

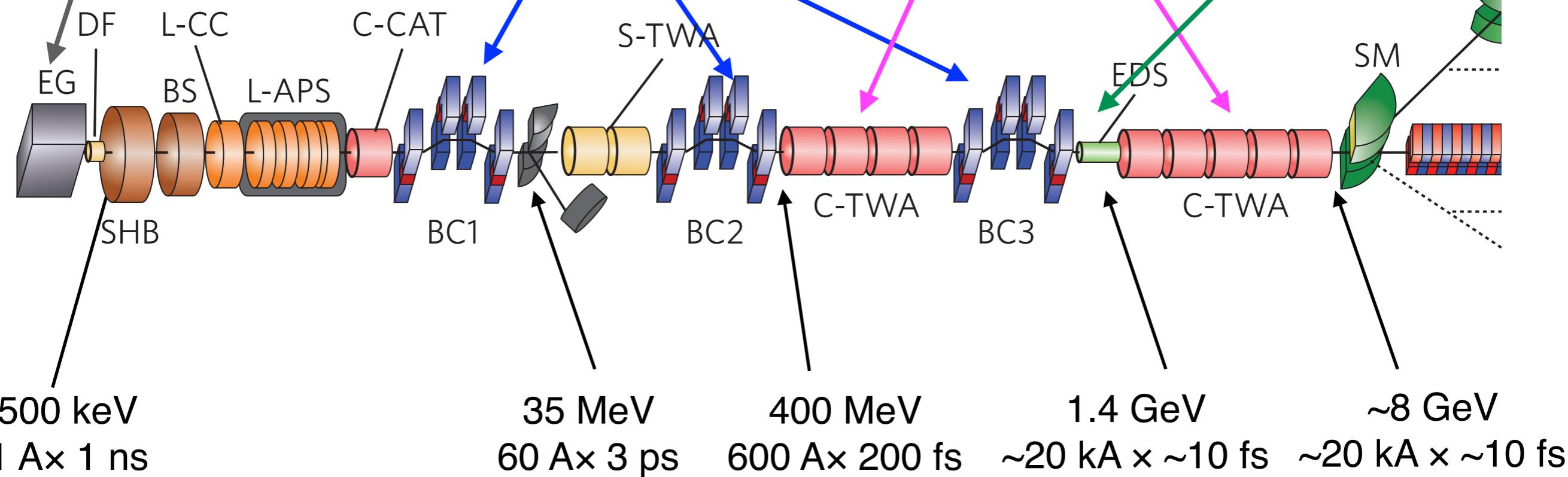
Bunch compression
chicane



C-band traveling wave
accelerator tube

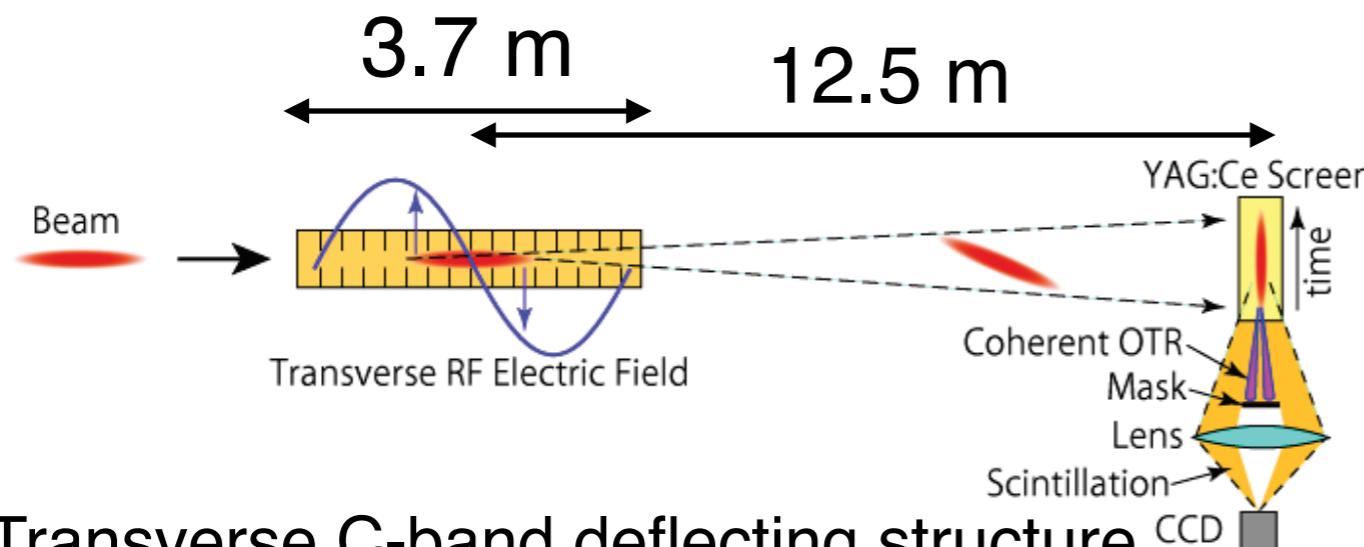


E-bunch diagnostic
(RF deflector)

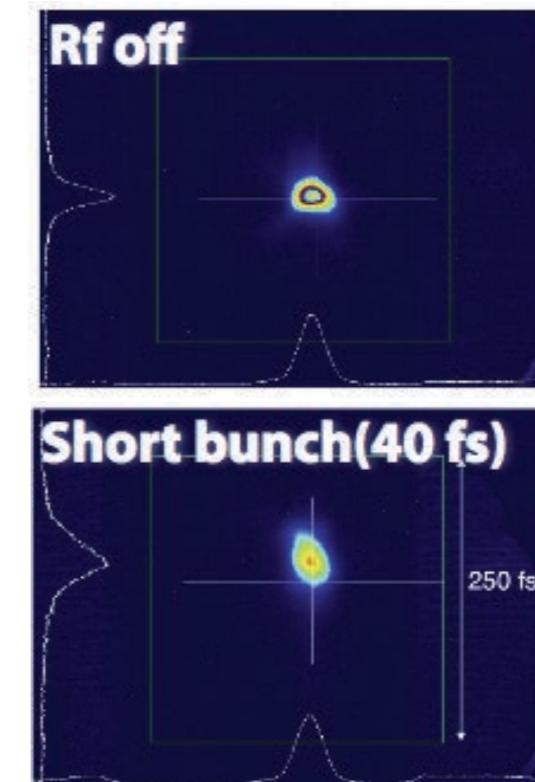


T. Ishikawa *et al.*, Nat. Photon. (2012).

Longitudinal diagnostic by RF deflector

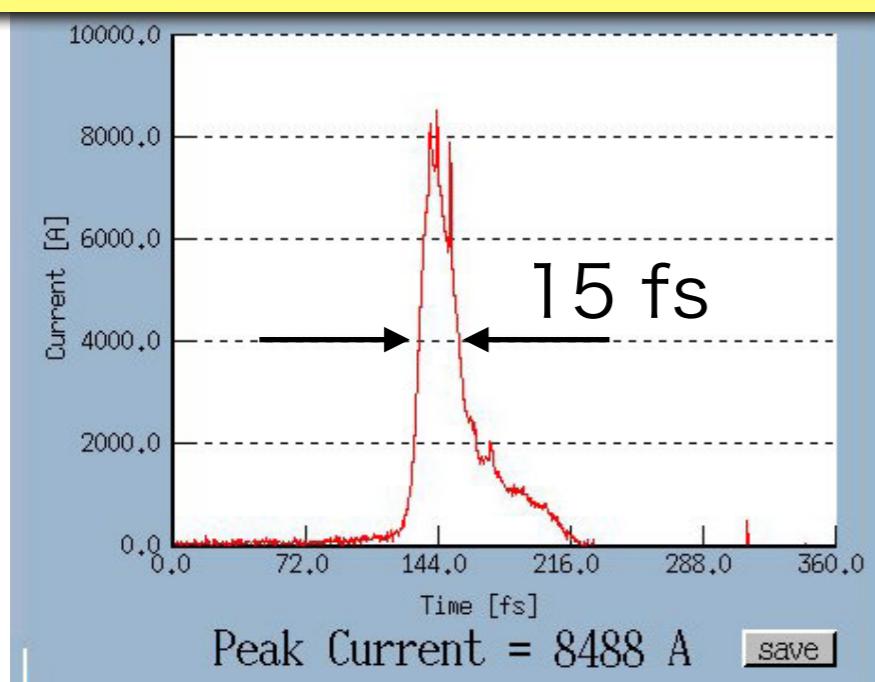


- Transverse C-band deflecting structure
- Deflecting voltage: ~60 MV
- Time resolution: 10-20 fs
- ← mainly determined by the projection size of e-beam



H. Ego *et al.*, NIMA 795, 381 (2015).

Typical temporal profile of e-bunch measured by RF deflector

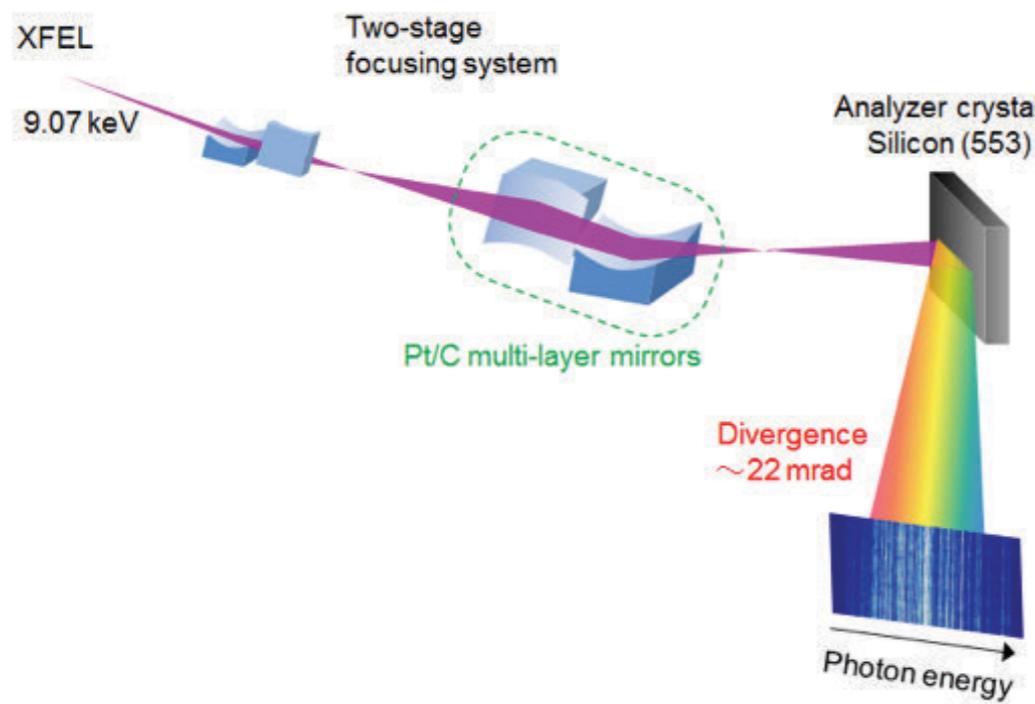


- Measured e-bunch duration is comparable to the time resolution of the deflector
- E-bunch duration is less than 15 fs

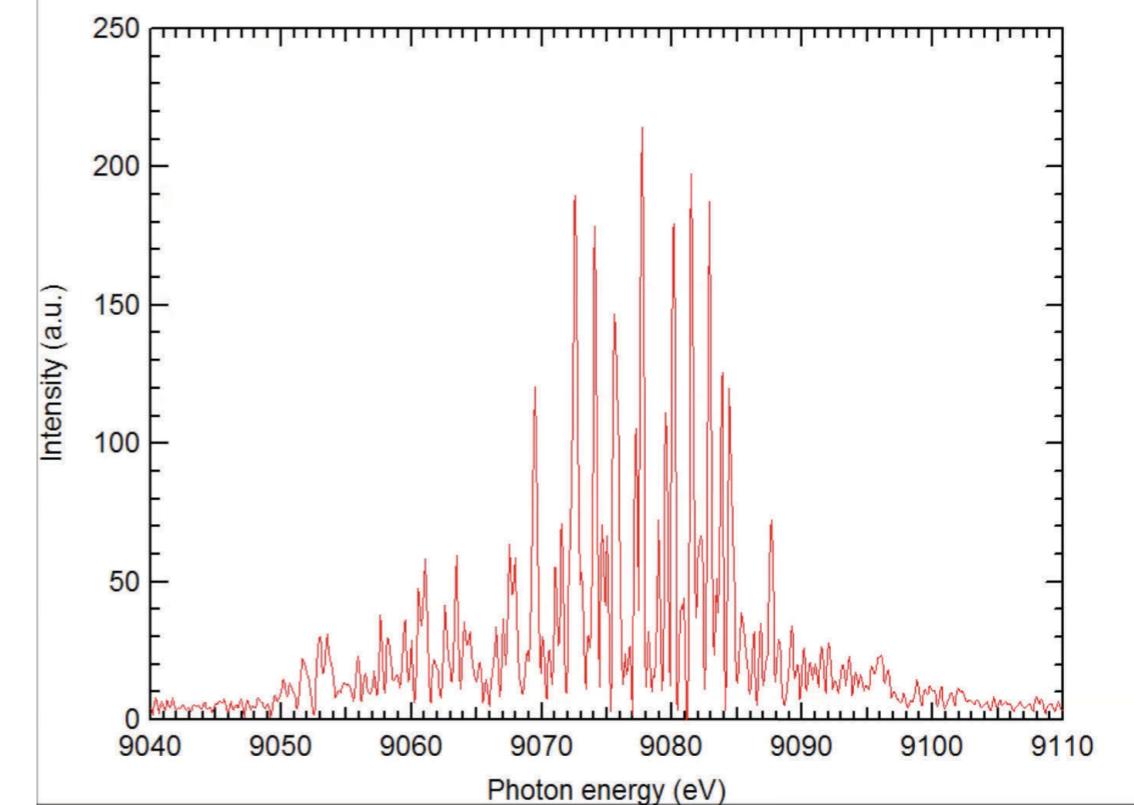
Measurement of XFEL duration @SACLA

Experiment

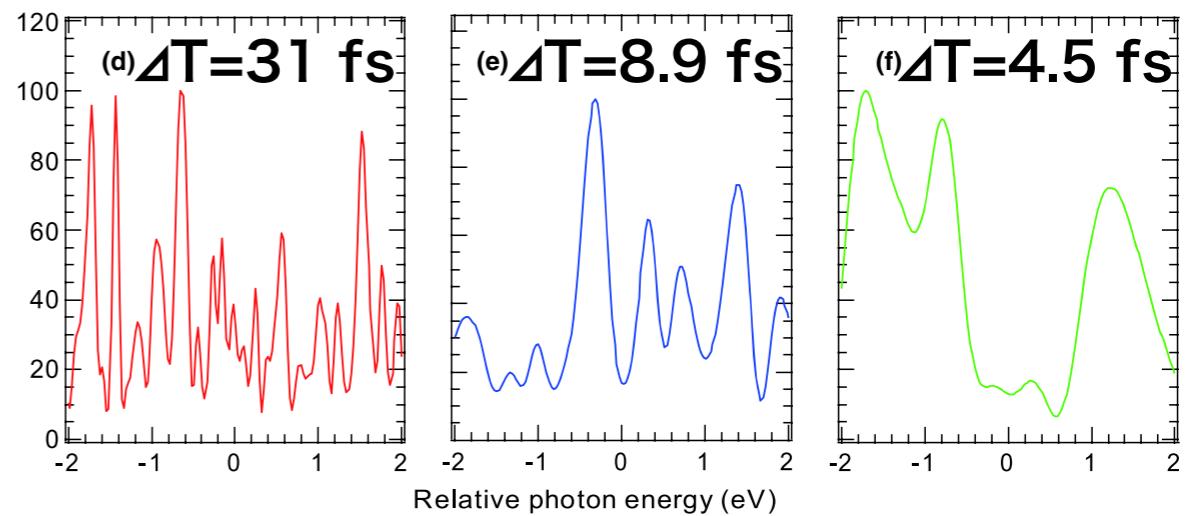
Single-shot spectrum + FEL simulation



X-ray pulse duration@SACLA:
6-8 fs (FWHM)



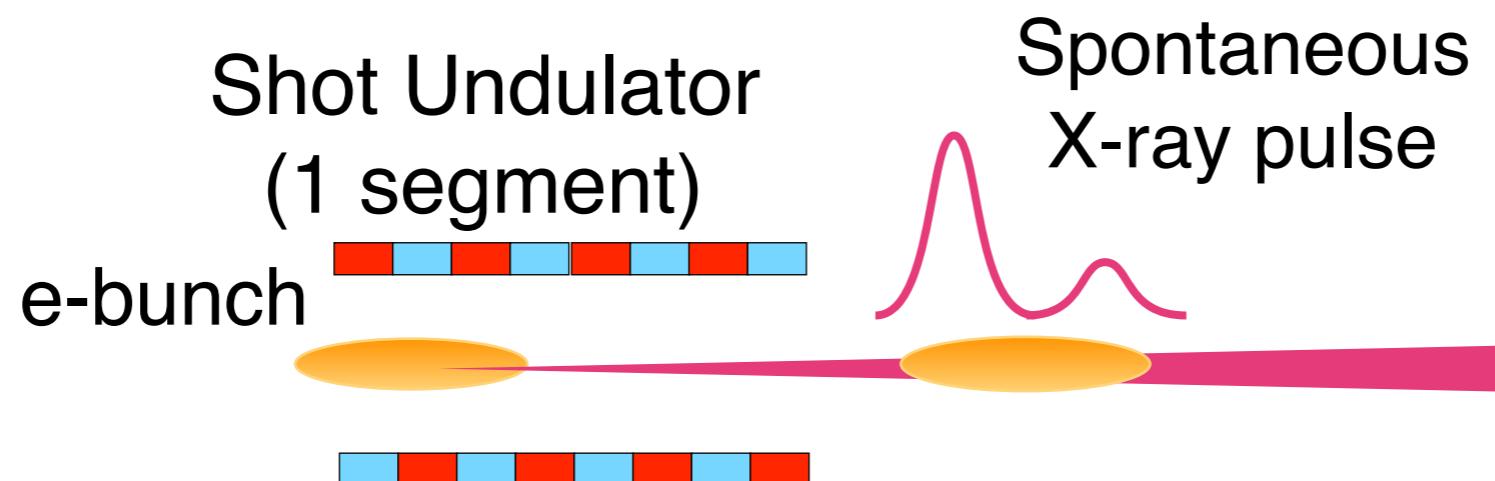
Simulation



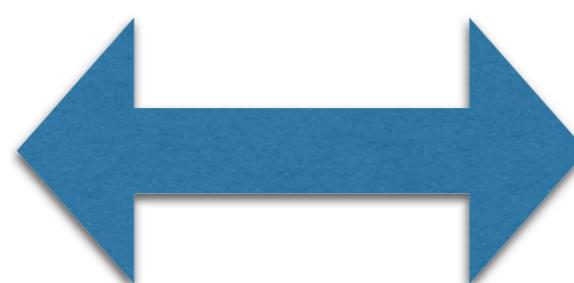
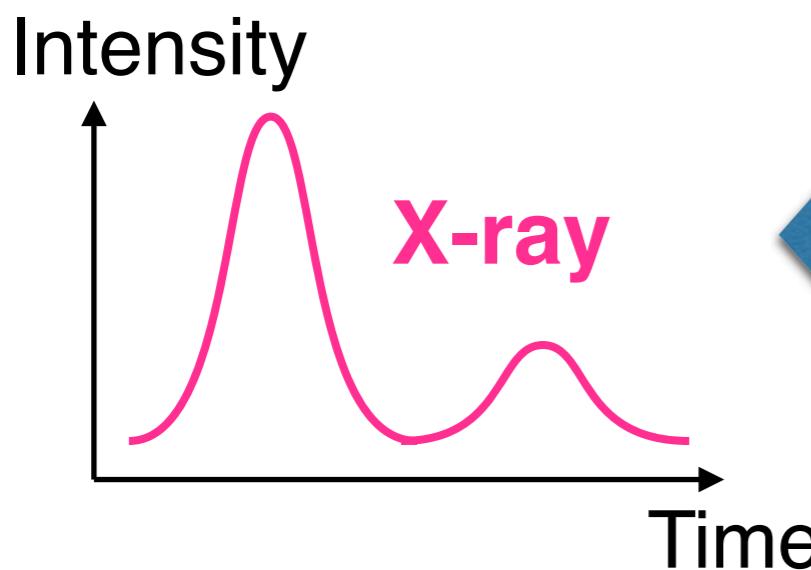
E-bunch duration should be comparable or less than 10 fs

Inubushi, *PRL* (2012).
Inubushi, Inoue, *Appl. Sci.* (2017).

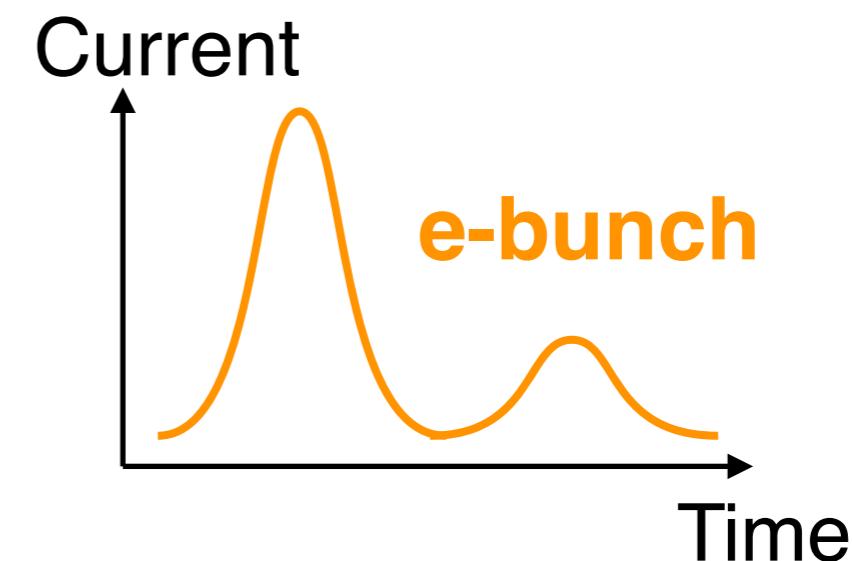
How to improve the resolution of longitudinal diagnostics ?



**Temporal profile of
the X-ray pulse**



**Current profile of
the e-bunch**



Shapes are almost identical
(slippage of e-beam is
negligibly small:
~ a few tens of attoseconds)

Temporal diagnostic of X-ray beam

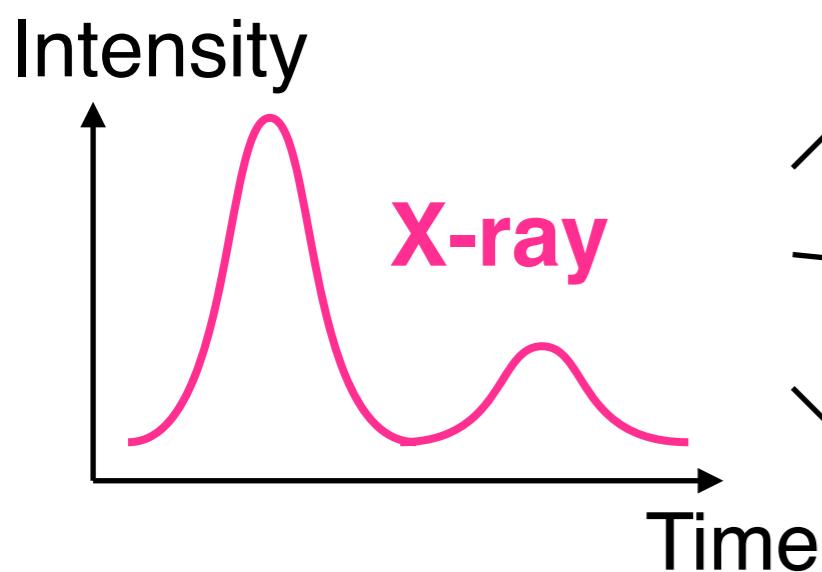
High speed camera



Photron 50th
未来へつなぐ信頼と創造

Max. frame rate:
 $\sim 10^6$ frame/s
($\sim 1 \mu\text{s}/\text{frame}$)

<https://www.photon.co.jp/>



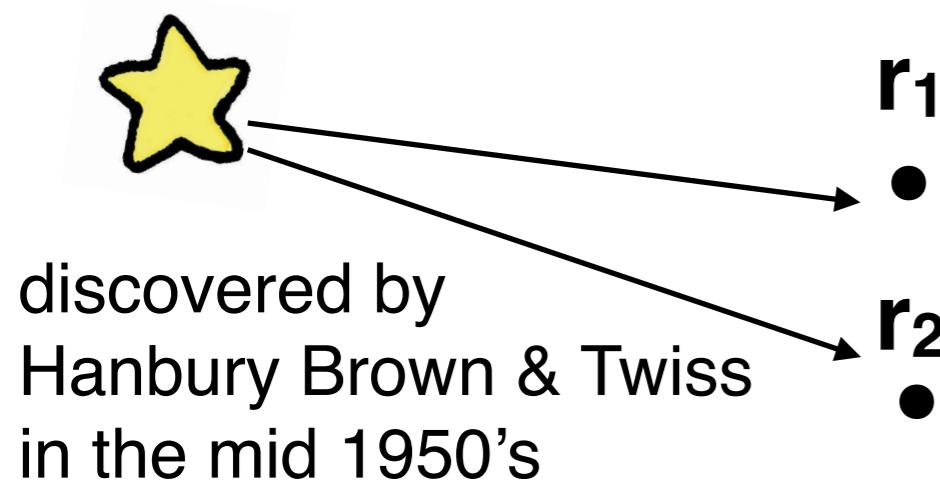
HAMAMATSU
PHOTON IS OUR BUSINESS

Max. time resolution:
500 fs

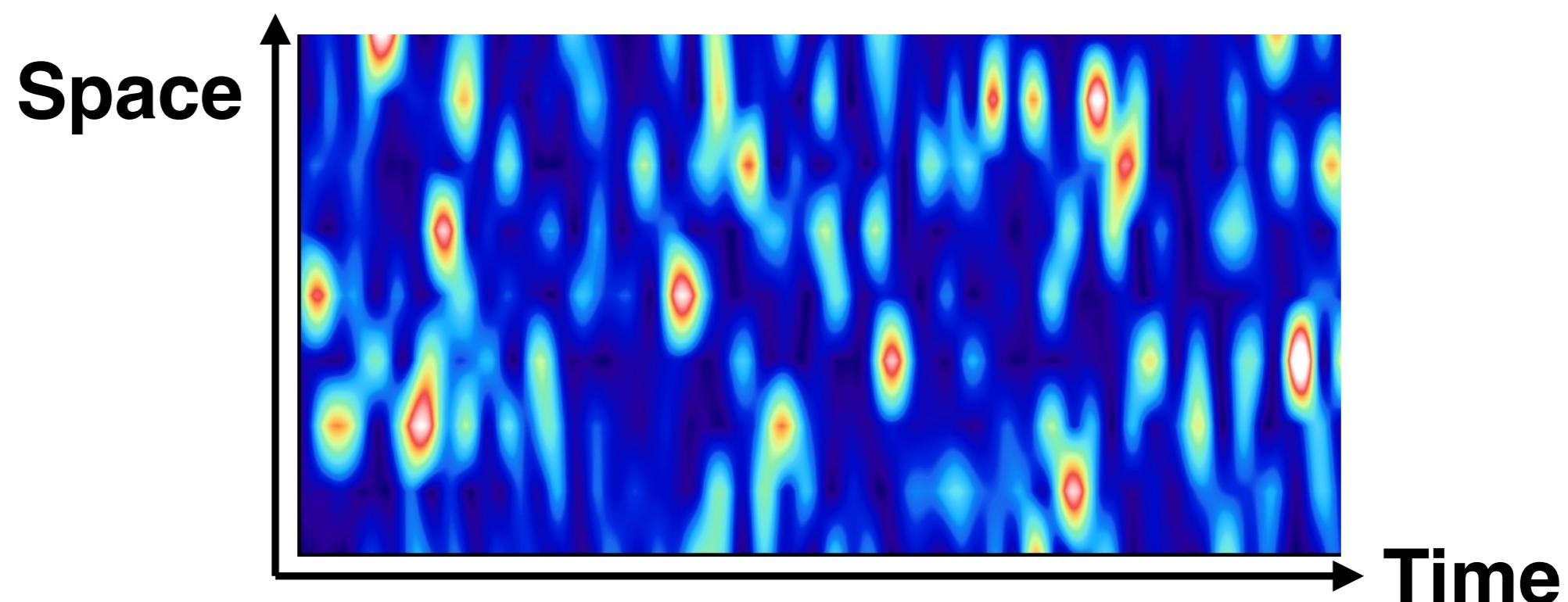
<https://www.hamamatsu.com/>

Intensity interferometry of
spontaneous X-rays from e-bunch

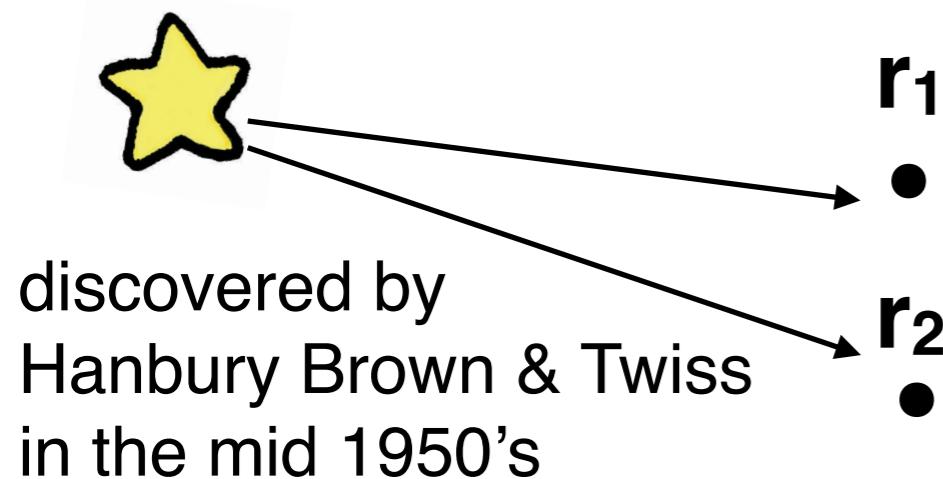
Intensity interference of chaotic light



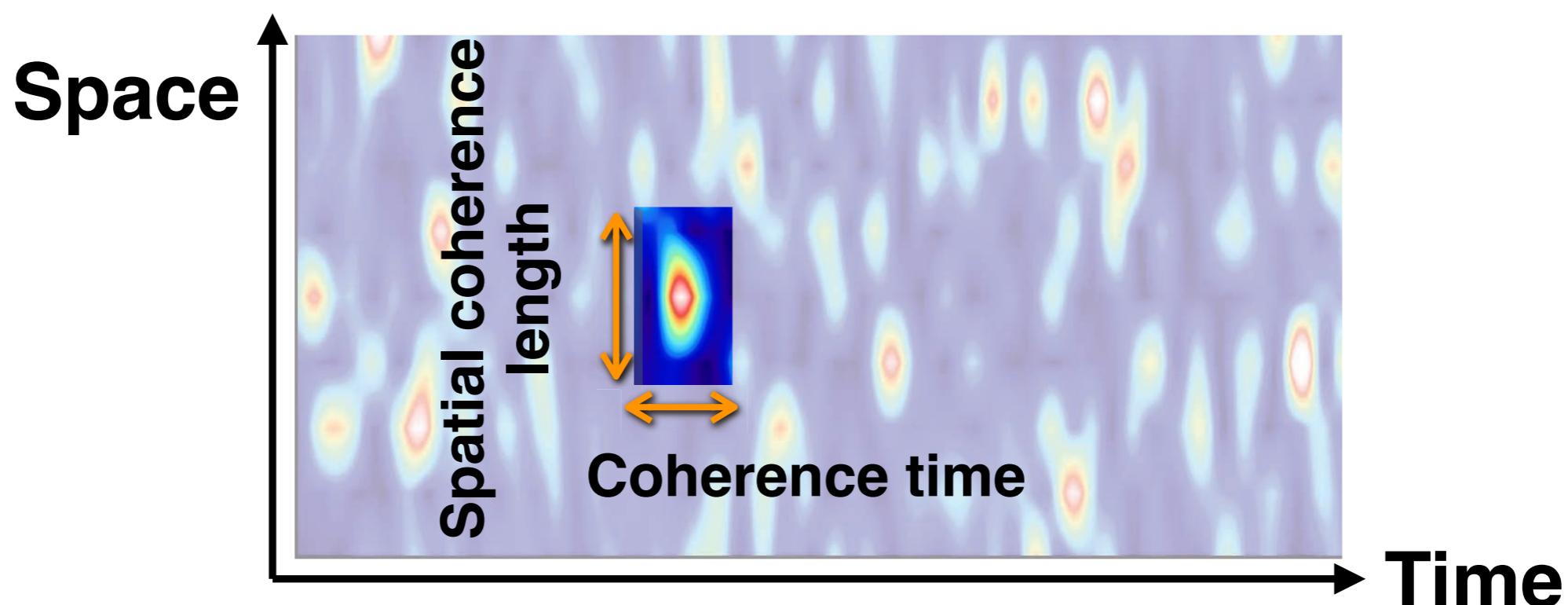
Intensities of chaotic light within spatial and temporal coherence lengths are correlated
"photons in chaotic light tend to be bunched"



Intensity interference of chaotic light

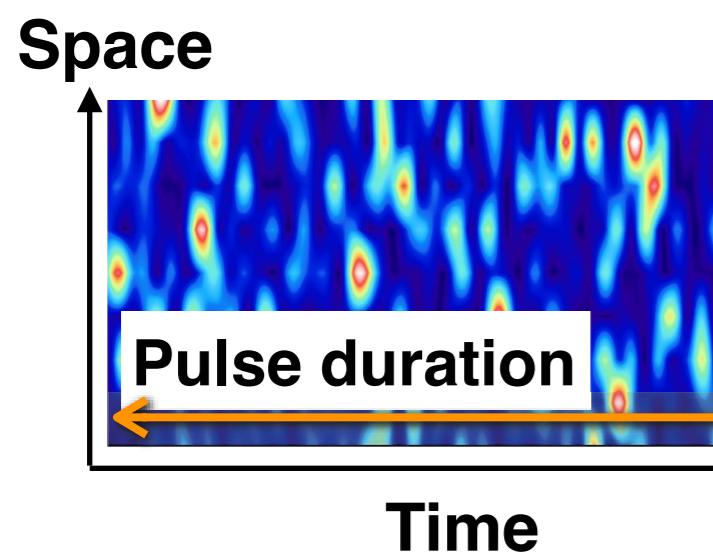


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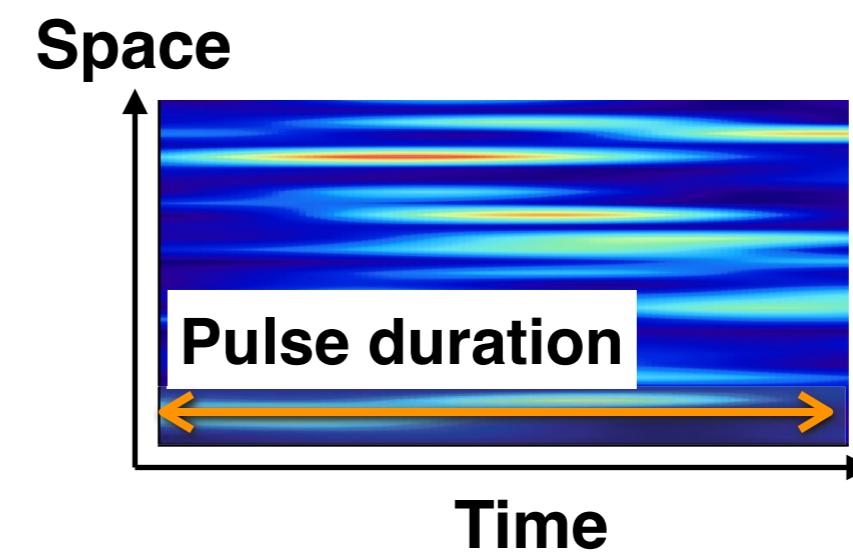
Time-integrated intensity interference in pulsed light

pulse duration > coherence time



No correlation of
time-integrated intensities at
separated positions

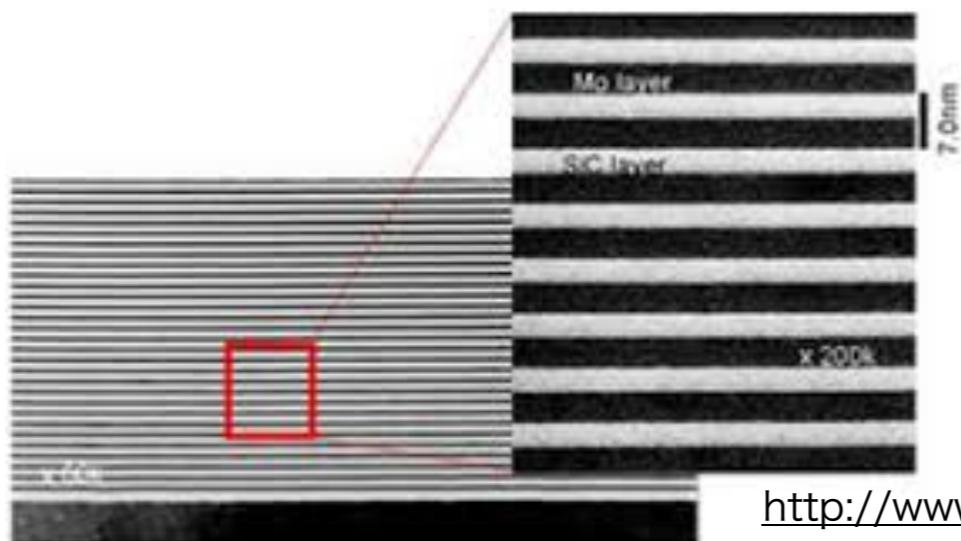
pulse duration \simeq coherence time



Strong correlation of
time-integrated intensities
within spatial coherence length

By changing the coherence time of the optical pulse and measuring the degree of time-integrated intensity interference, we can determine the temporal intensity profiles of optical pulses.

Coherence time achievable by X-ray optical devices



Multilayer

$$\Delta E/E = 10^{-2} - 10^{-3}$$

Coherence time : 10-100 as

[http://www.ntt-at.com/
product/multilayer/](http://www.ntt-at.com/product/multilayer/)

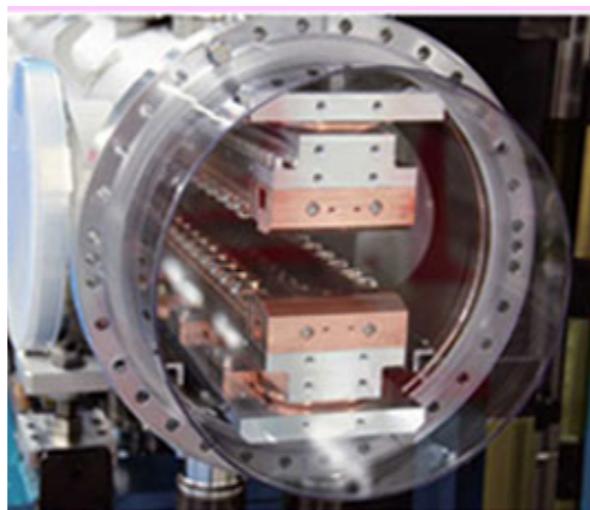


<https://www.saint-gobain.co.jp/>

Crystal monochromator

$$\Delta E/E = 10^{-3} - 10^{-8}$$

Coherence time : 100 as-10 ps



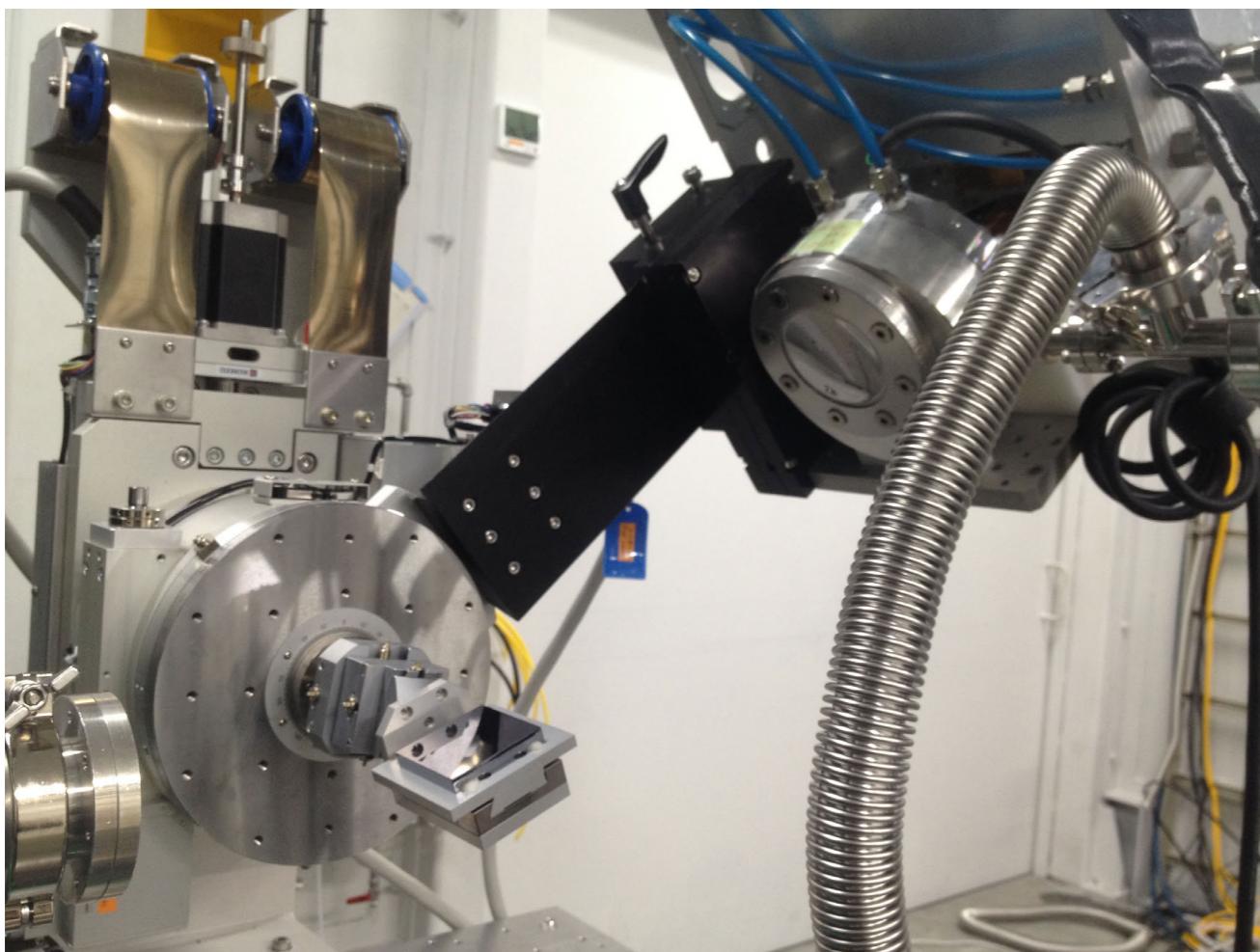
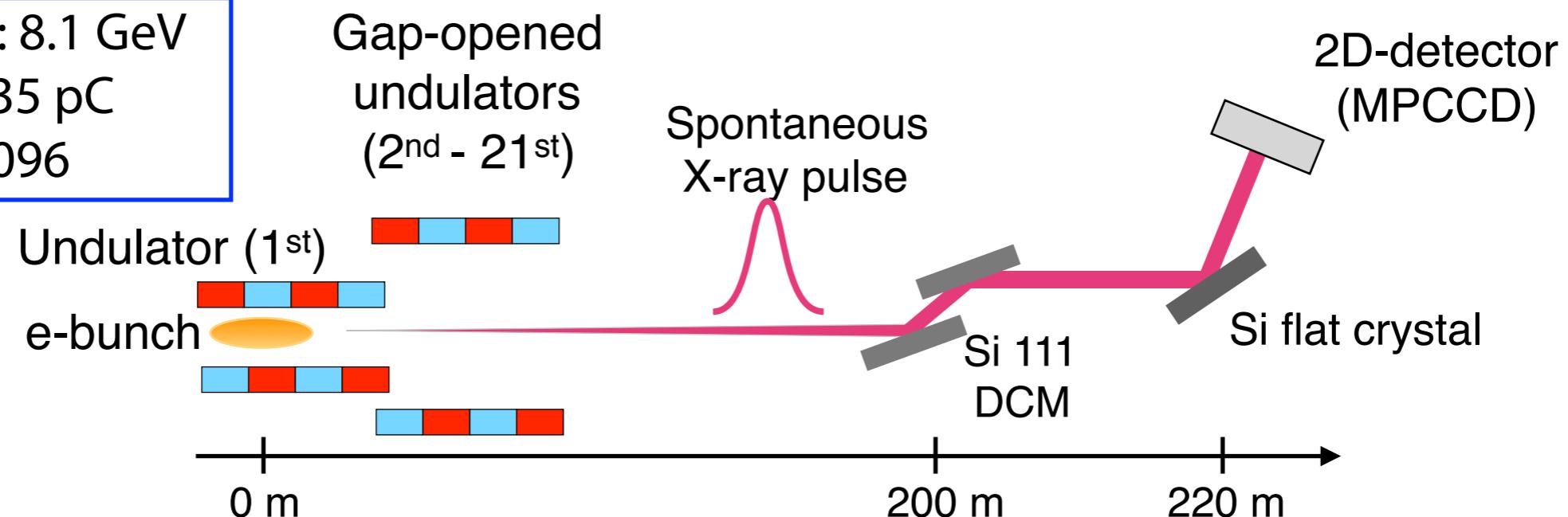
Undulator radiation itself

$$\Delta E/E \sim 10^{-1} - 10^{-2}$$

Coherence time : 1 as-10 as

Intensity interferometry @SACLA BL3 (10.5 keV XFEL)

- e-beam energy: 8.1 GeV
- Total charge: 235 pC
- K parameter: 2.096



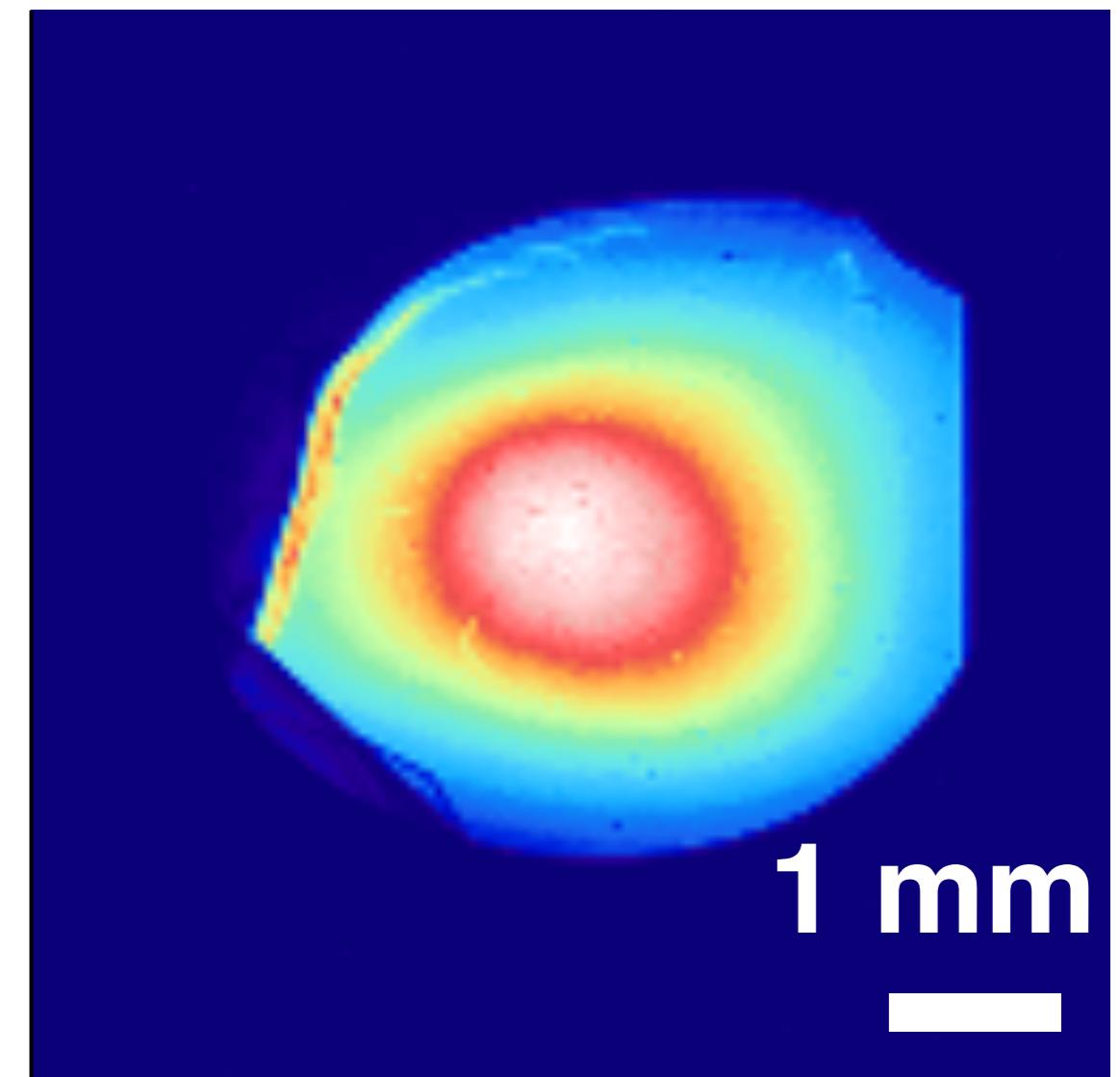
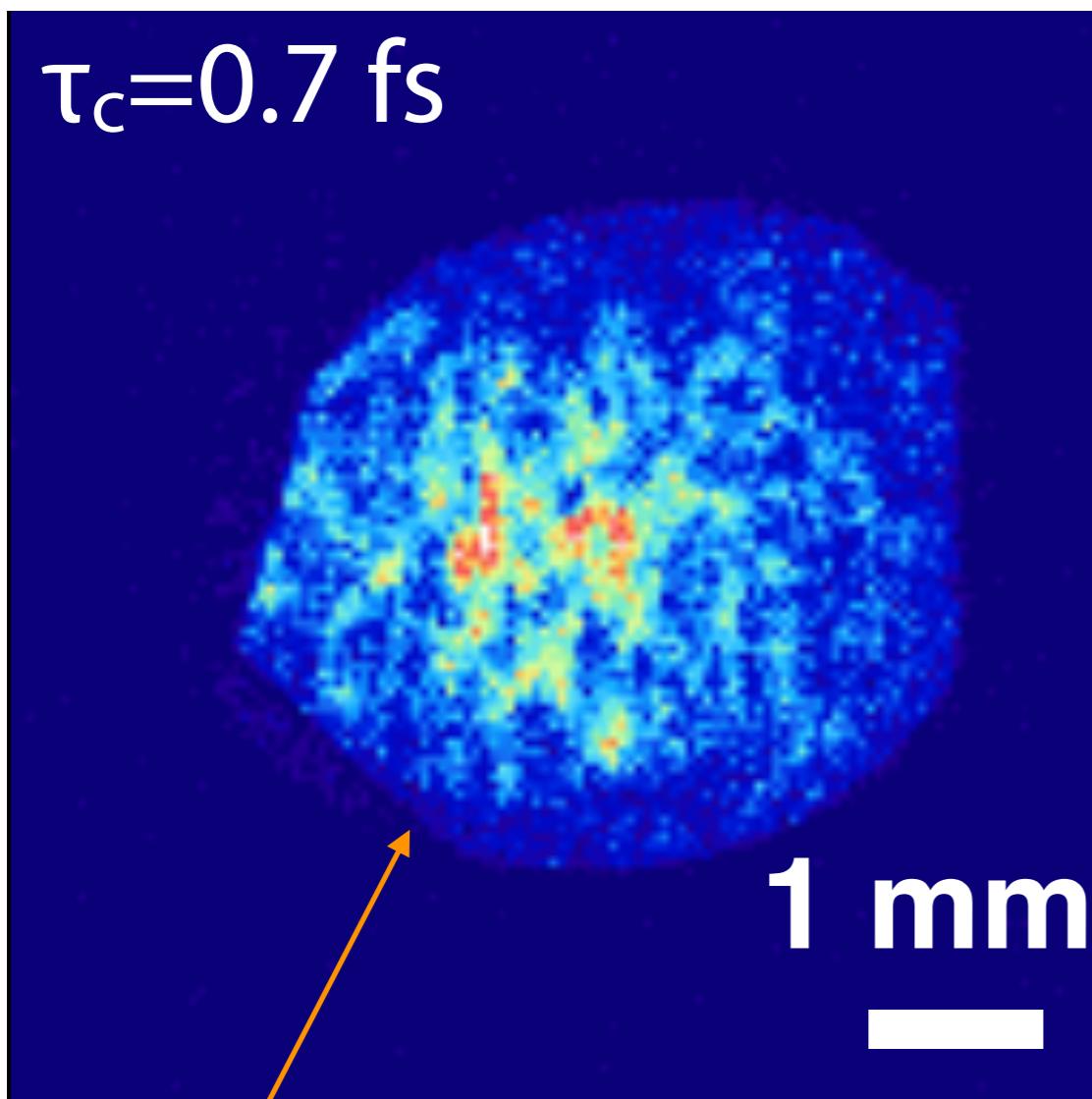
Reflective index	Coherence time
111	0.8 fs
220	1.3 fs
311	2.6 fs
440	7.7 fs
333	8.4 fs
444	14.8 fs
660	30.9 fs
555	46.4 fs

coherence time
 $\tau_c = 1/(2\sigma_\omega)$
frequency spread
of X-ray beam
after monochromator

Single-shot image of spontaneous X-ray pulse

Spontaneous X-ray radiation
monochromatized by Si 111 reflection

cf. Averaged image over
multiple pulse



Some portions of the X-ray beam is cut
due to the limited aperture
of the beamline

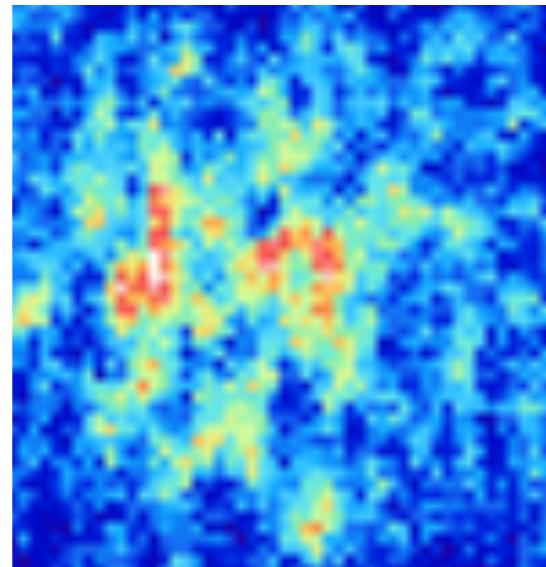
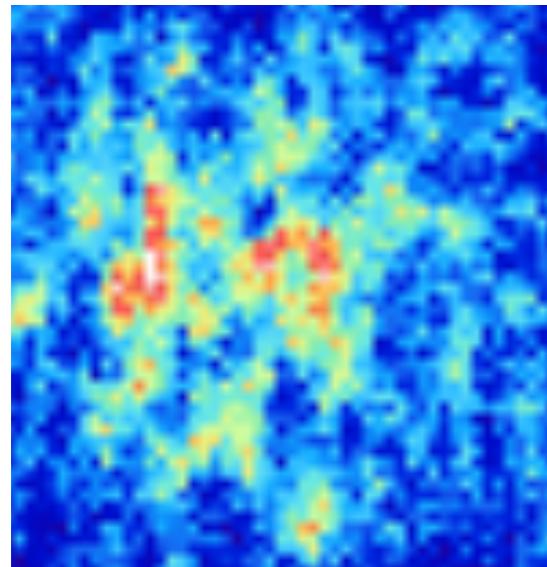
I. Inoue *et al.*, PRAB 21, 080704 (2018).

Quantitative analysis of intensity interference

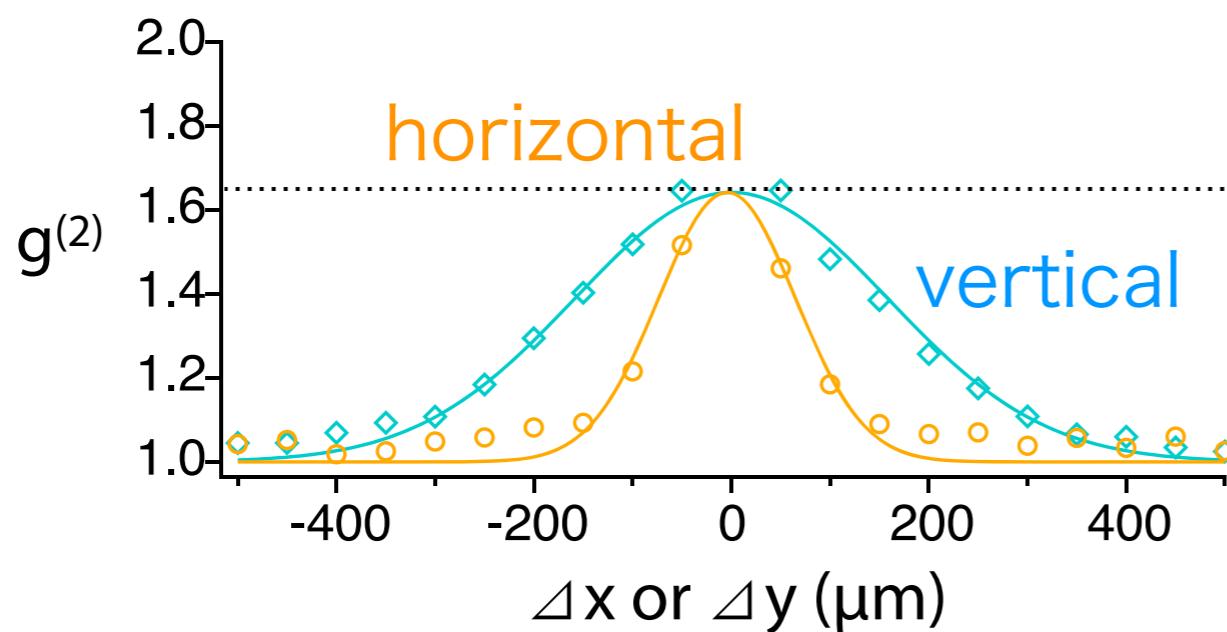
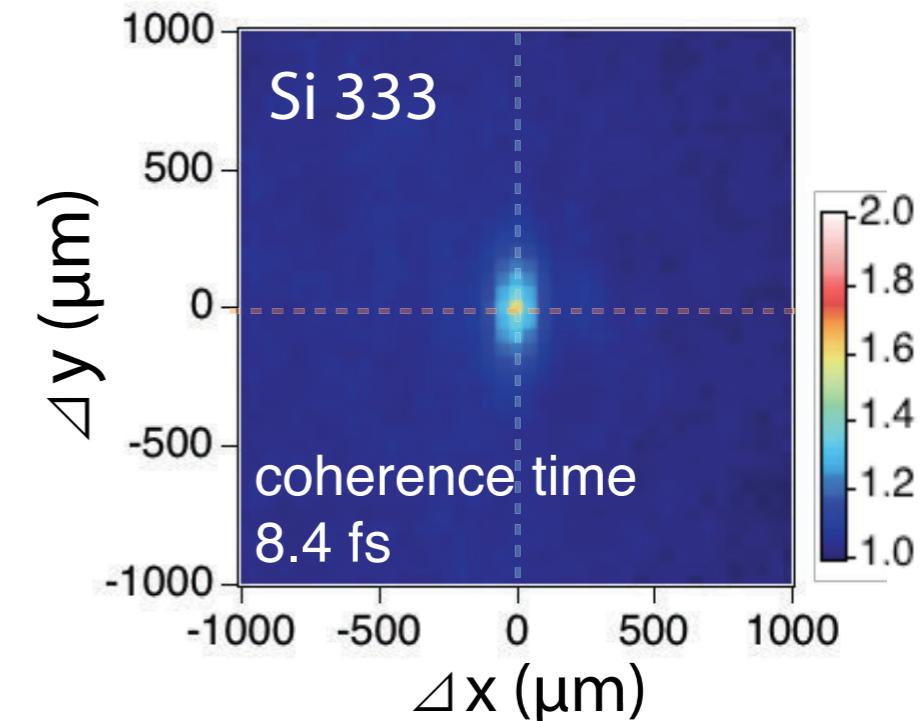
Normalized intensity correlation functions (“2D autocorrelation”)

$$g^2 = \frac{\langle I^t(r_0)I^t(r_0 + \Delta r) \rangle}{\langle I^t(r_0) \rangle \langle I^t(r_0 + \Delta r) \rangle}$$

$\langle \rangle$: average over different pulses



=



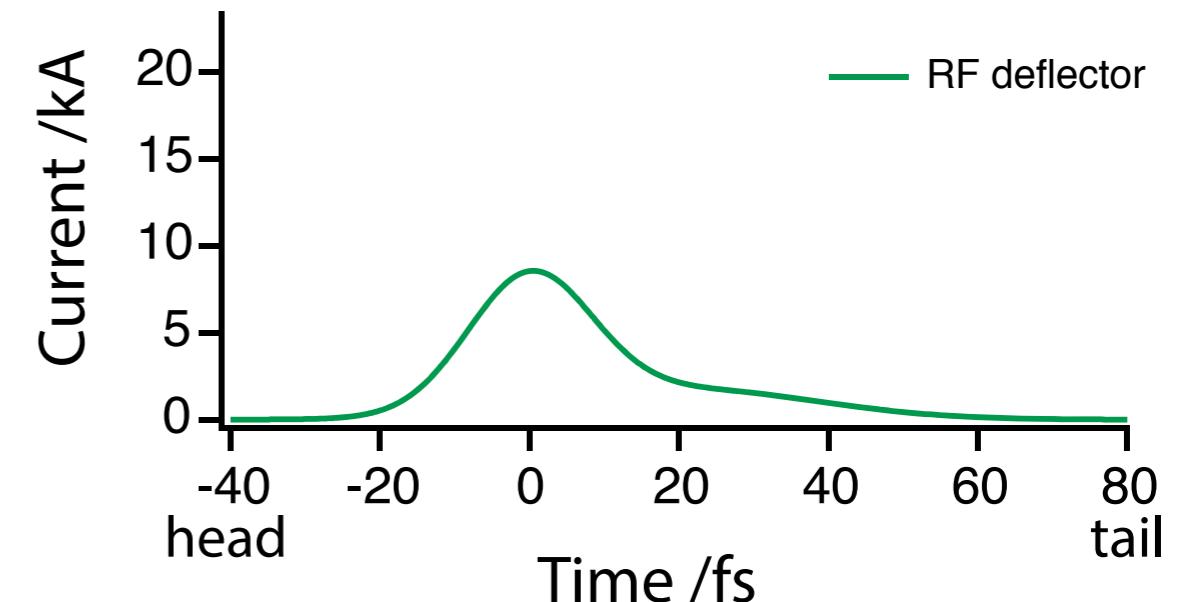
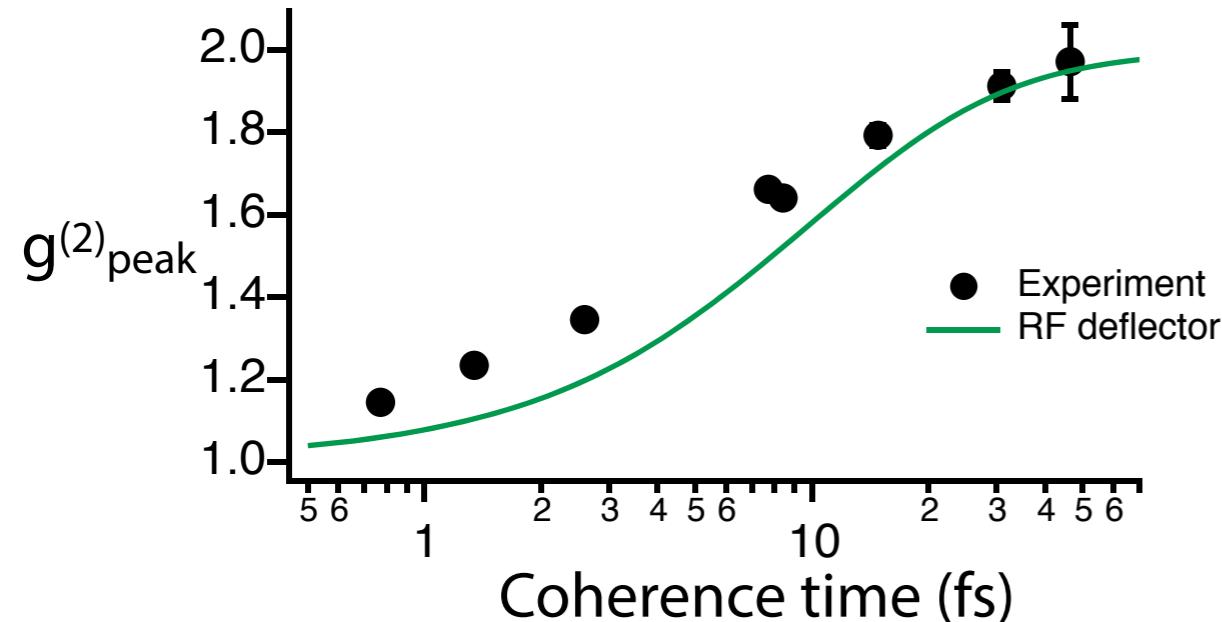
Width:

spatial coherence length

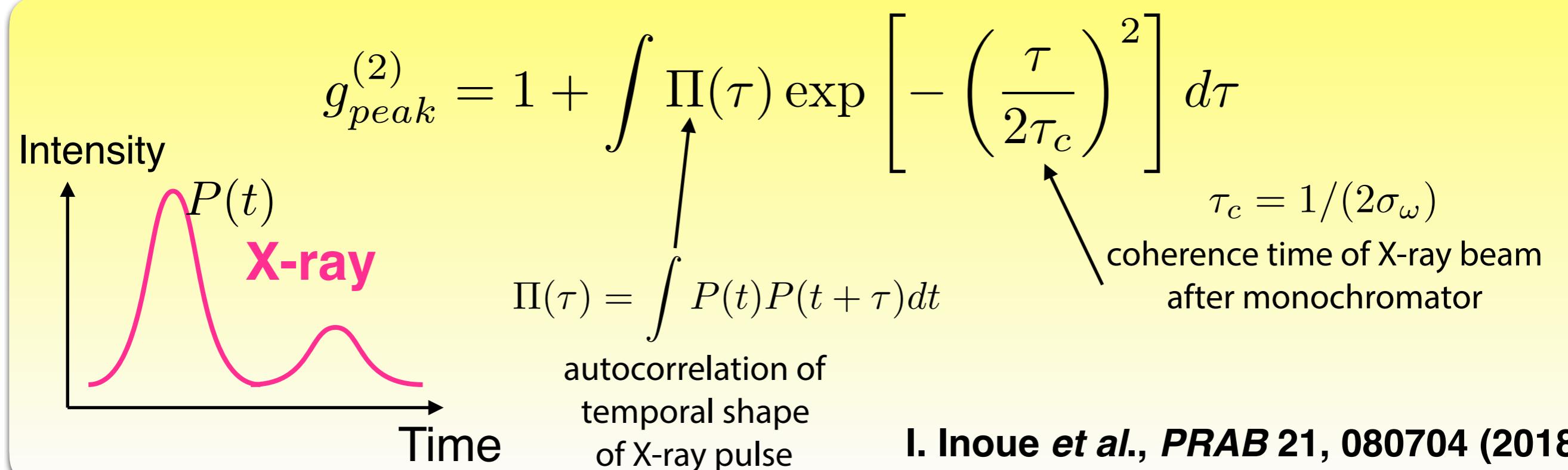
Peak value:

determined by magnitude relationship between coherence time and pulse duration

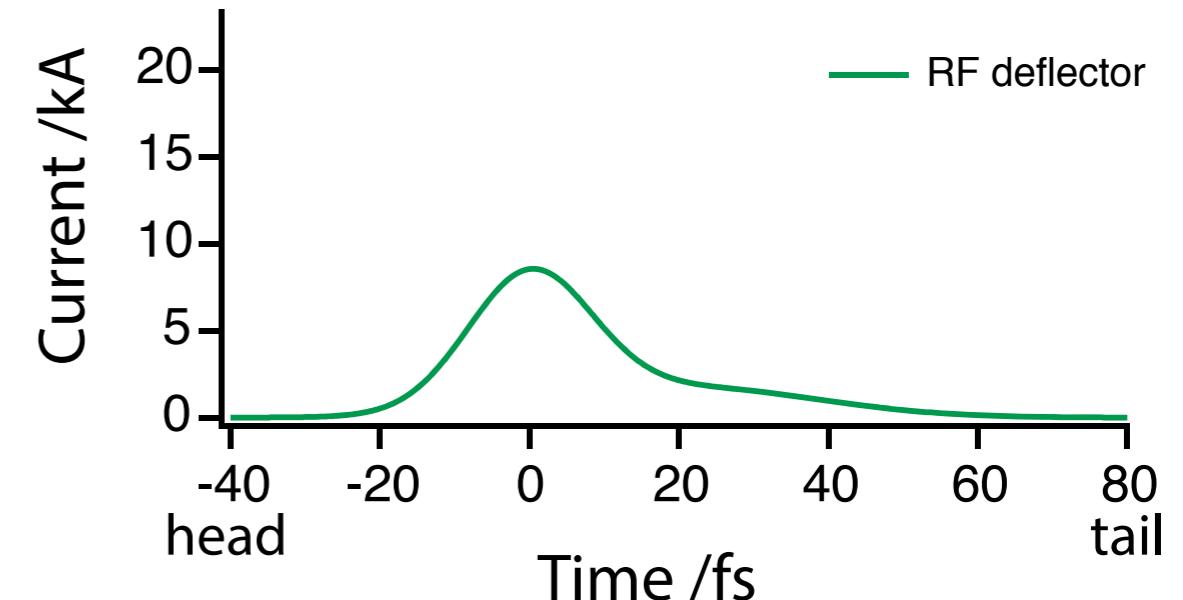
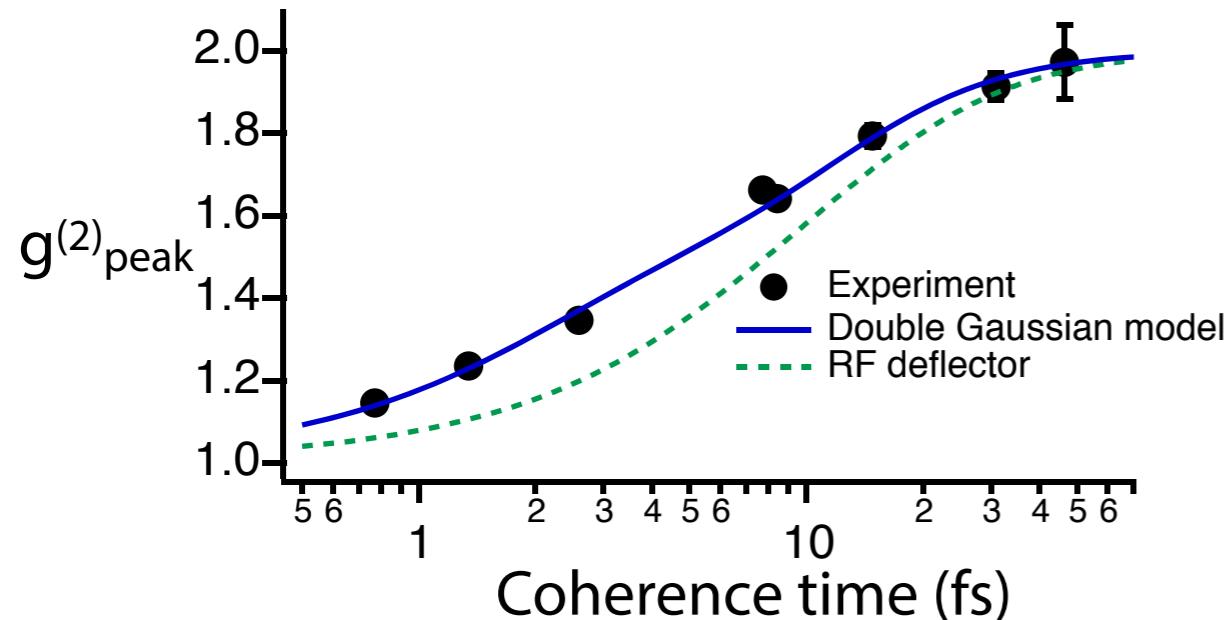
Determination of e-bunch profile by intensity interferometry



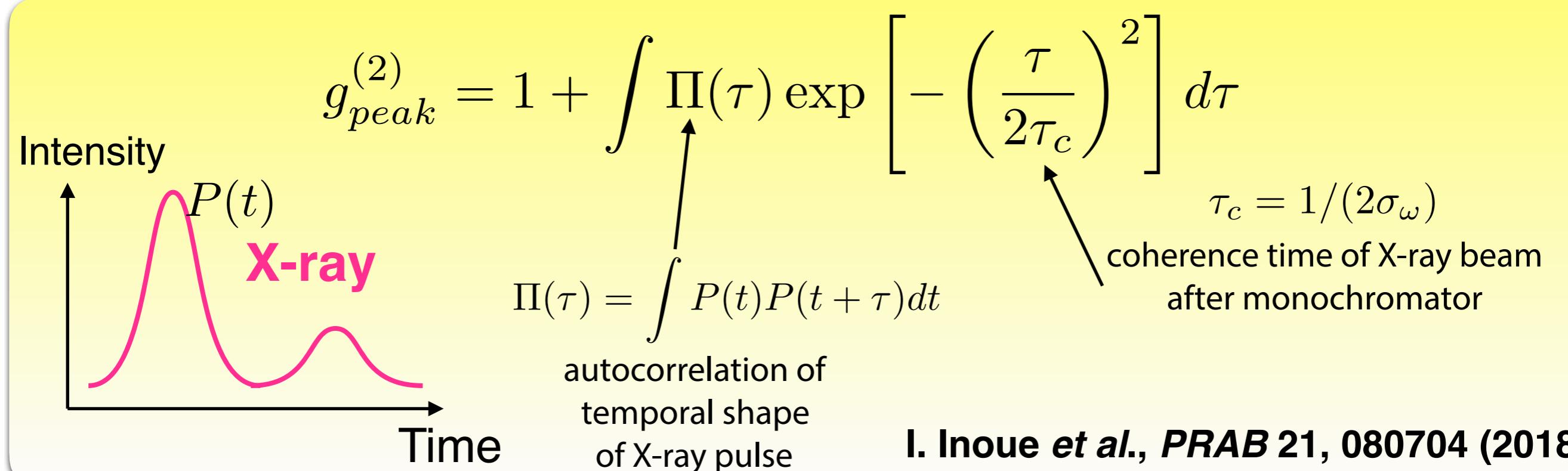
Relationship between g^2_{peak} and coherence time



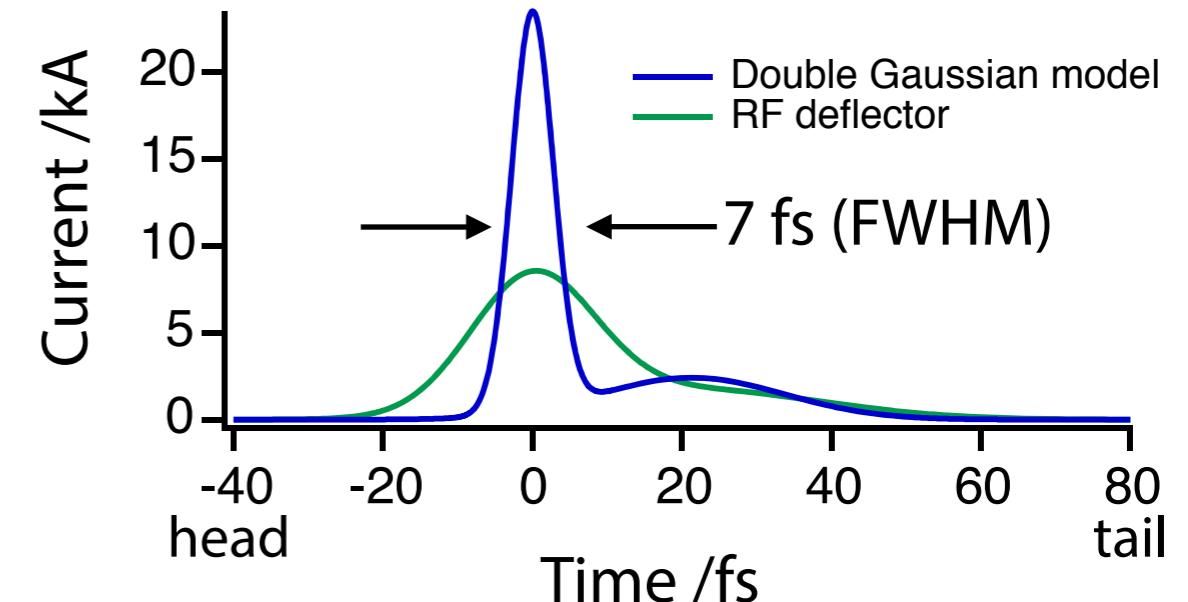
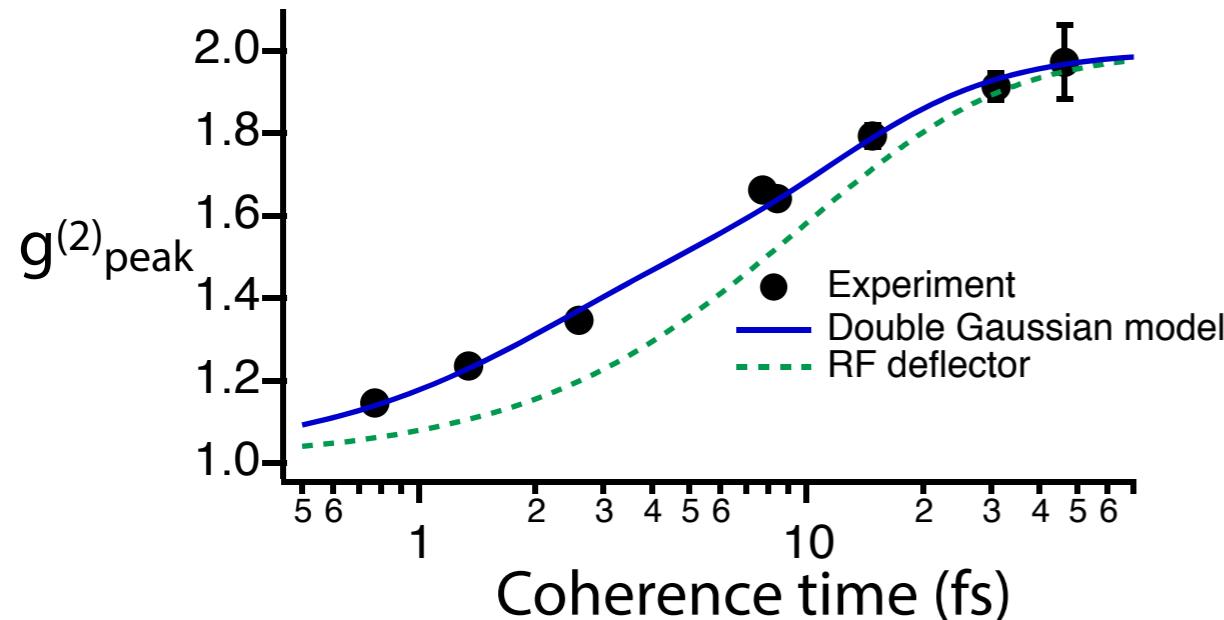
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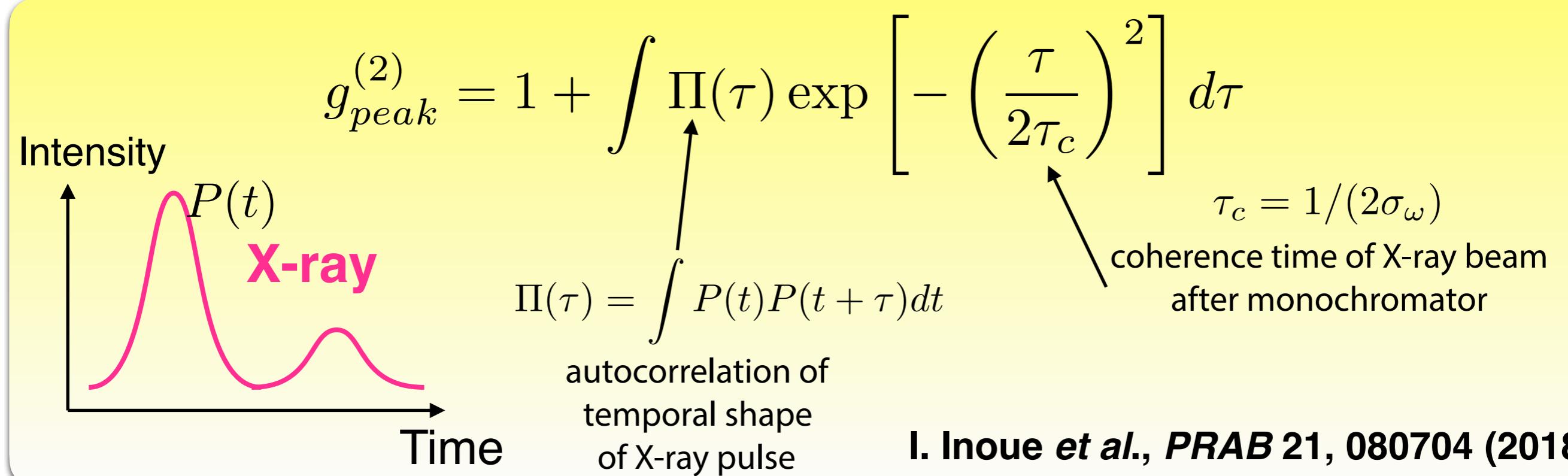
Relationship between g^2_{peak} and coherence time



Determination of e-bunch profile by intensity interferometry



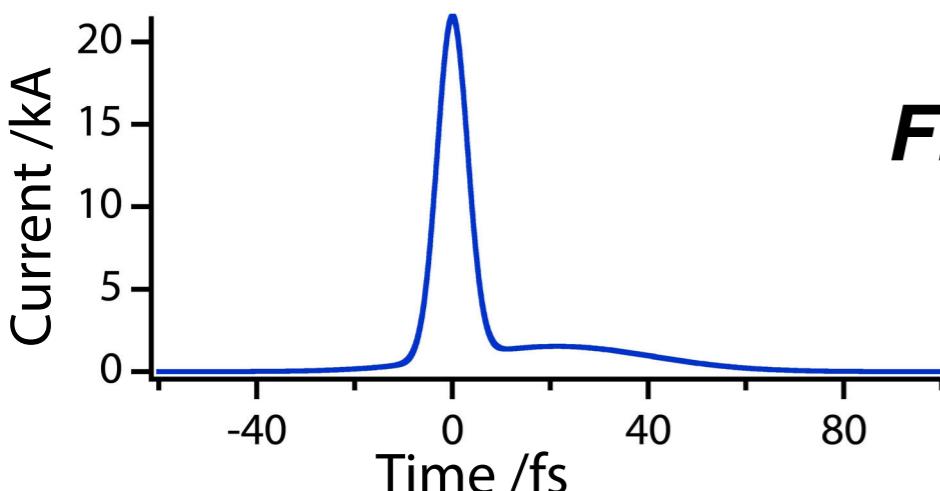
Relationship between g^2_{peak} and coherence time



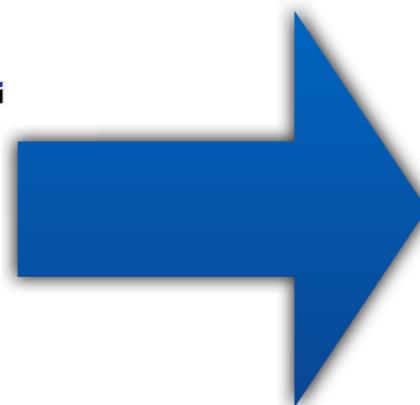
I. Inoue *et al.*, PRAB 21, 080704 (2018).

Evaluation of XFEL pulse duration

Temporal profile of e-bunch



*FEL simulation
(SIMPLEX)*

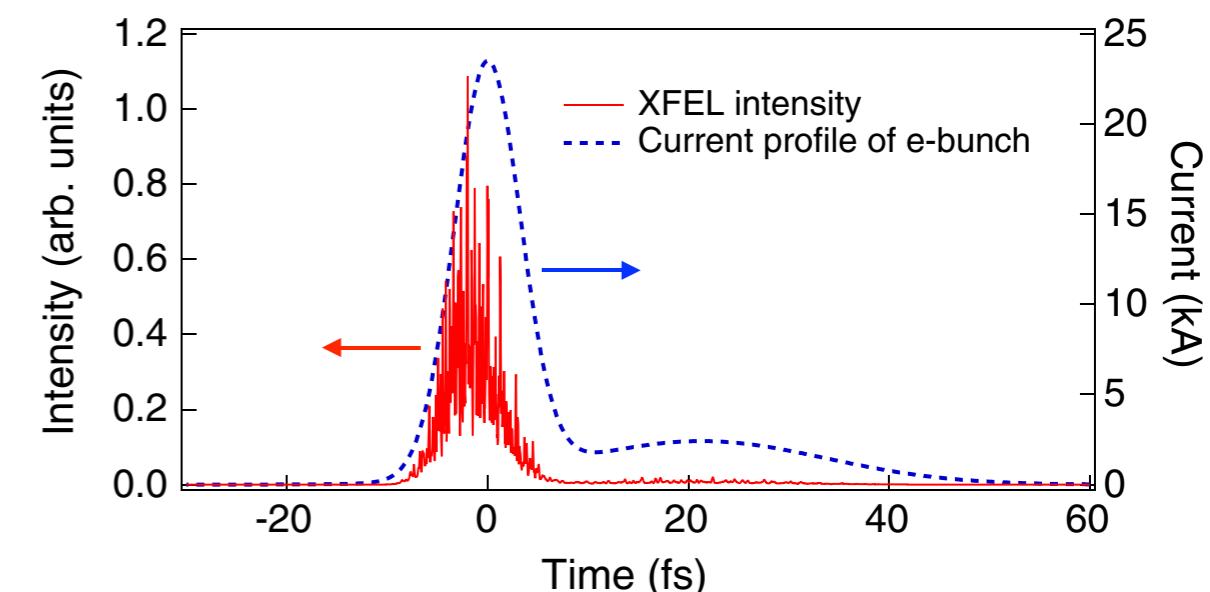


+Other parameters

- ★ emittance
- ★ energy spread
- ★ energy chirp
- ★ betatron function

etc...

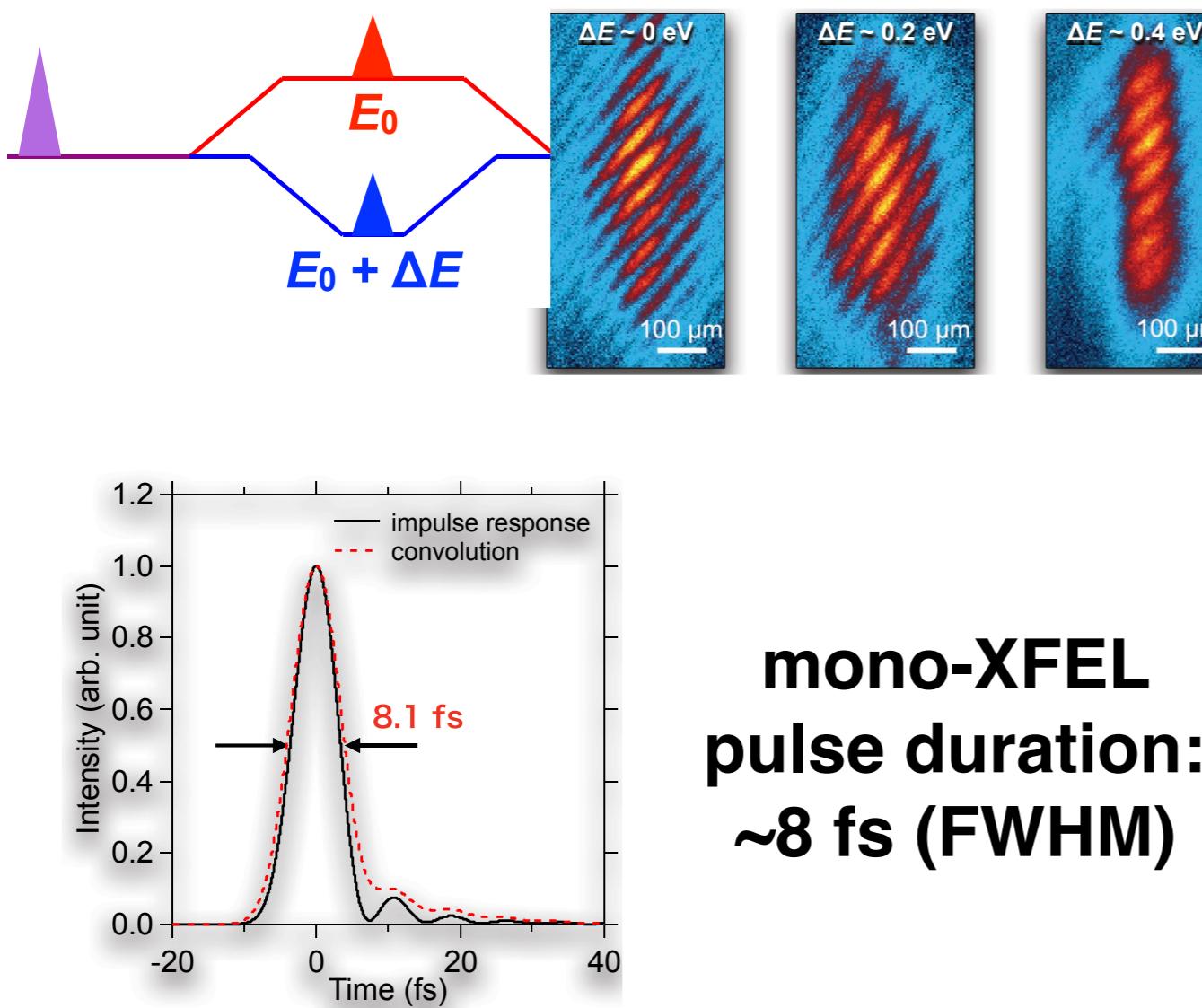
Temporal profile of XFEL pulse (10.5 keV)



- High current region of e-bunch selectively emit intense X-rays
- XFEL duration is ~7 fs (FWHM)

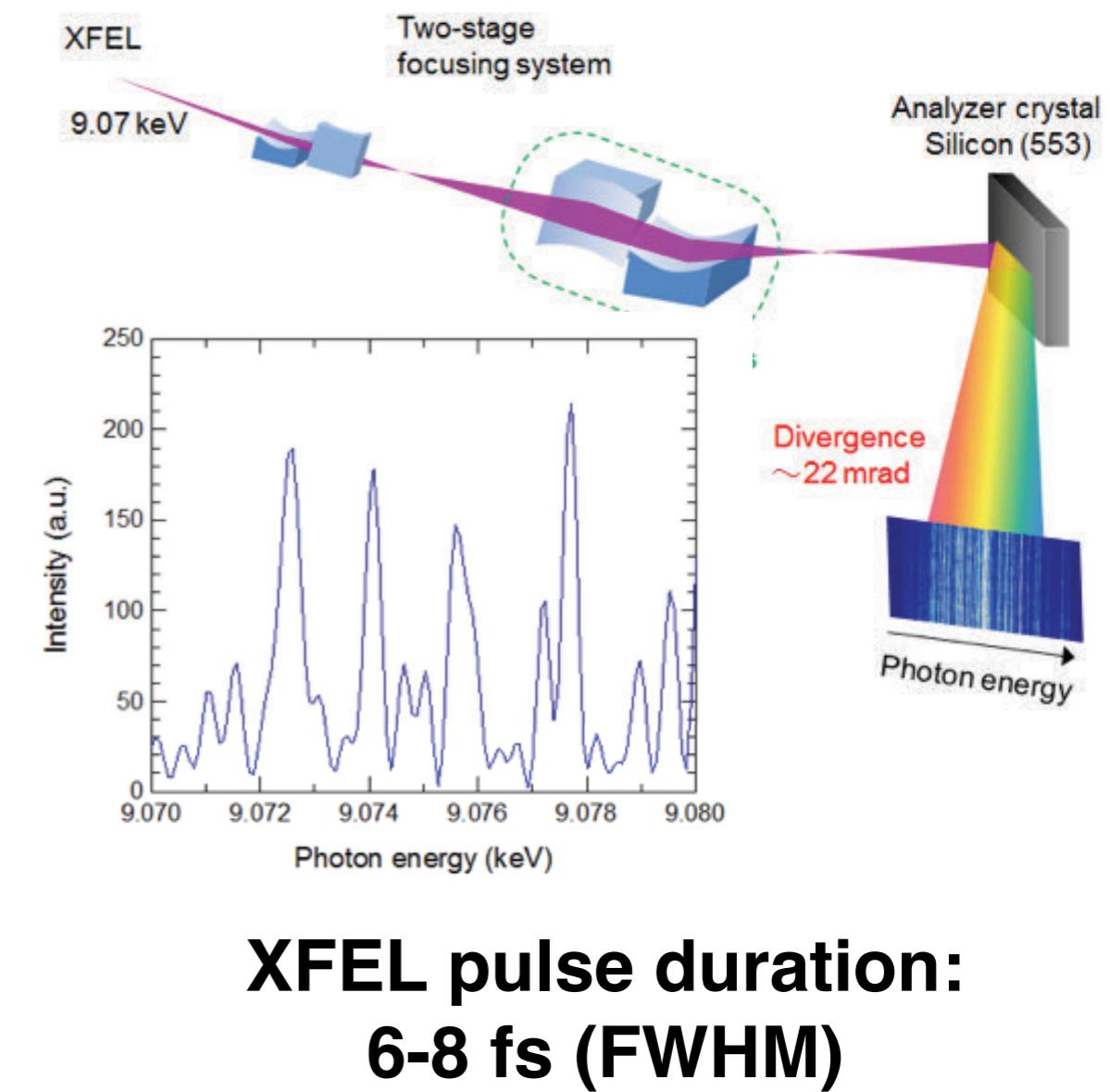
Comparison with other diagnostic methods

Interferometry of XFELs with different wavelengths



Osaka *et al.*, *in preparation*.

High-resolution spectrum



Inubushi, Inoue, *Appl. Sci.* (2017).

Summary

- Intensity interferometry for temporal diagnostic of e-bunch/XFELs has been proposed and demonstrated.
- Our scheme is applicable to much shorter e-bunches since the coherence time of X-rays can be controlled to attosecond region with X-ray optical devices.
- This scheme is cost effective and easily conducted.
→should be useful for cross-checking with other diagnostic systems.
- Single-shot temporal diagnostic scheme based on intensity interferometry is under development.